



**TekExpress Ethernet Tx
Compliance Solution
Application Help**



077-1253-03





**TekExpress Ethernet Tx
Compliance Solution
Application Help**

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Contacting Tektronix

Tektronix, Inc.

14150 SW Karl Braun Drive

P.O. Box 500

Beaverton, OR 97077

USA

For product information, sales, service, and technical support:

- In North America, call 1-800-833-9200.
- Worldwide, visit www.tek.com to find contacts in your area.

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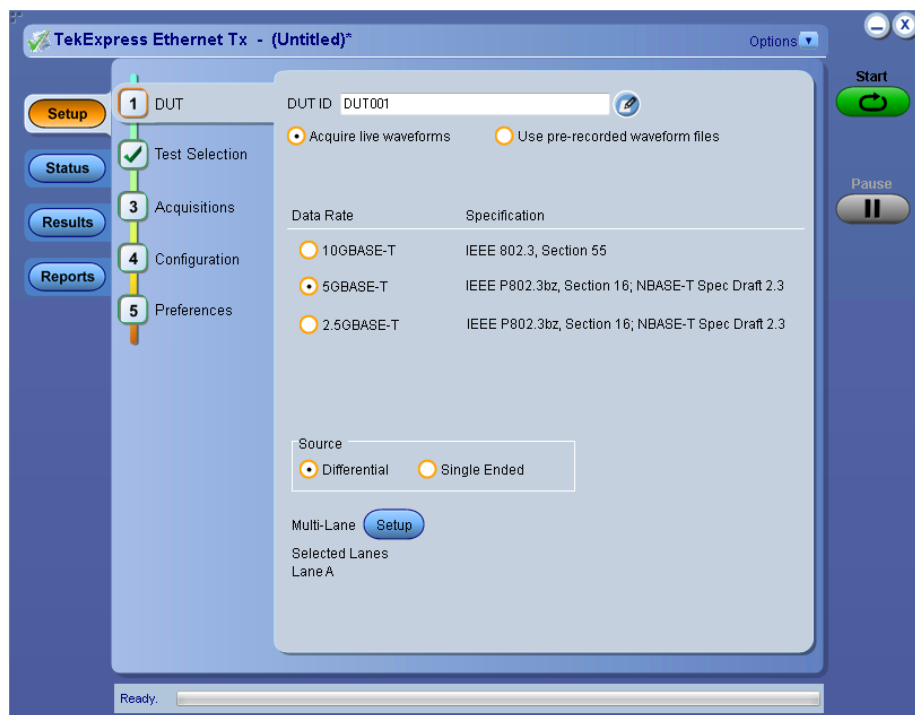
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Welcome

Welcome to the TekExpress® Ethernet NBASE-T Conformance Solution. The application provides turnkey testing & characterization solution for 10GBASE-T measurements as outlined in IEEE 802.3 Section 55, and for 5GBASE-T and 2.5GBASE-T as outlined in IEEE P802.3bz, Section 16; NBASE-T Spec Draft 2.3. Automation options help the customers to meet their conformance testing needs and generate detailed reports. User-defined Mode lets customers make changes to the test limits and perform margin testing as part of extended product characterization.



Key features of TekExpress Ethernet Tx include:



- Comprehensive automated solution for NBASE-T, 2.5GBASE-T, 5GBASE-T and 10GBASE-T testing
- One-button selection of multiple tests and four-channel support
- Detailed test reports with margin and statistical information aid analysis
- User-defined mode enables flexible parameter control for characterization and margin analysis
- Single instrument analysis of time- and frequency-domain measurements
- Signal acquisition and analysis support for differential probes or direct SMA cabling

Getting help and support

Related documentation

The following documentation is available as part of the TekExpress® Ethernet Tx Solution application.

Table 1: Product documentation




Item	Purpose	Location
Help	Application operation and User Interface help	
PDF of the help	Printable version of the compiled help	 PDF file that ships with TekExpress Ethernet Tx Solution software distribution (TekExpress Ethernet-Tx-Automated-Test-Solution-Software- Printable-Help-EN-US.pdf).

Conventions

Help uses the following conventions:

- The term "Application," and "Software" refers to the TekExpress Solution application.
- The term "DUT" is an abbreviation for Device Under Test.
- The term "select" is a generic term that applies to the two methods of choosing a screen item (button, control, list item): using a mouse or using the touch screen.

Table 2: Icon descriptions

Icon	Meaning
	This icon identifies important information.
	This icon identifies conditions or practices that could result in loss of data.
	This icon identifies additional information that will help you use the application more efficiently.

Technical support

Tektronix values your feedback on our products. To help us serve you better, please send us your suggestions, ideas, or comments on your application or oscilloscope. Contact Tektronix through mail, telephone, or the Web site, www.tek.com.

When you contact Tektronix Technical Support, please include the following information (be as specific as possible):

General Information

- All instrument model numbers
- Hardware options, if any
- Probes used
- Your name, company, mailing address, phone number, FAX number
- Please indicate if you would like to be contacted by Tektronix about your suggestion or comments.

Application Specific Information

- Software version number
- Description of the problem such that technical support can duplicate the problem
- If possible, save the setup files for all the instruments used and the application.
- If possible, save the TekExpress setup files, log.xml, *.TekX (session files and folders), and status messages text file.
- If possible, save the waveform on which you are performing the measurement as a .wfm file.

Getting started

Minimum system requirements

The following table shows the minimum system requirements to install and run the application.

Table 3: System requirements

Component	Description	
Oscilloscope	Supported Scopes	Data Rate
	DPO7254C	2.5GBASE-T and 5GBASE-T
	DPO7354C	2.5GBASE-T, 5GBASE-T, and 10GBASE-T
	DPO/DSA/MSO70000C	
	DPO/DSA70000D	
	DPO/MSO70000DX	
	DPO/MSO70804DX	
	DPO/MSO71254DX	
	DPO/MSO71604DX	
	DPO/MSO72004DX	
	DPO/DPS70000SX	
	DPO72004SX and DPO72504SX	
Table continued...		

Component	Description	
Signal Generators	AWG AWG5002B/C AWG5004B AWG5012B/C AWG5014B/C AWG70002A AWG7082C AWG7122C AWG70001B AWG70002B AWG70002A	Supported for Return Loss and Transmitter non-linear distortion (2.5GBase-T, IEEE P802.3bz, Section 16; NBASE-T Spec Draft 2.3)
	AFG AFG3052C AFG3102/C AFG3152C AFG3252/C AFG31000 AFG31102 AFG31152 AFG31252	Supported for Transmitter non-linear distortion (2.5GBase-T, IEEE P802.3bz, Section 16; NBASE-T Spec Draft 2.3)
Processor	Same as the oscilloscope	
Operating System	Windows 7	
Memory	Same as the oscilloscope	
Hard Disk	Same as the oscilloscope	
Display	Super VGA resolution or higher video adapter (800 x 600 minimum video resolution for small fonts or 1024 x 768 minimum video resolution for large fonts). The application is best viewed at 96 dpi display settings ¹	
Firmware	<ul style="list-style-type: none"> TekScope 7.6.5 or above 	
Software	<ul style="list-style-type: none"> IronPython 2.7.3 installed PyVisa 1.0.0.25 installed Microsoft .NET 4.0 Framework Microsoft Internet Explorer 7.0 SP1 or greater, or other Web browser for viewing reports Adobe Reader software 7.0 or greater for viewing portable document format (PDF) files 	

Table continued...

¹ If TekExpress is running on an instrument that has a video resolution less than 800x600, connect and configure a second monitor to the instrument.

Component	Description
Other Devices	<ul style="list-style-type: none"> Microsoft compatible mouse or compatible pointing device. Two USB ports (four USB ports recommended).

Supported Probes and Power splitter

The table gives the list of probes and power splitter recommended for the TekExpress Ethernet Tx application.

Table 4: Recommended probes

Oscilloscope Model	For Droop, PSD, Linearity, Clock Frequency, Jitter-Master and Jitter Slave measurements	For Return Loss measurement
DPO7354	P6330 – Minimum of one and maximum of four are required	P6330 – Minimum of two are required
	TDP3500 – Minimum of one and maximum of four are required	TDP3500 – Minimum of two are required
	SMA Cables – Minimum of two are required	NA
DPO70000 and MSO70000	P6330 – Minimum of one and a maximum of four are required	P6330 – Minimum of two are required
	P7330 , P7340A, P7350, P7360A, P7380A and P7313 – Minimum of one and maximum of four are required	P7330 , P340A, P7350, P7360A, P7380A and P7313 – Minimum of two are required
	Trimode probes (P7504, P7506, P7508, P7513A, P7516 & P7520A) – A minimum of one and maximum of four are required	Trimode probes (P7504, P7506, P7508, P7513A, P7516 & P7520A) – Minimum of two are required
	P7350SMA, P7380SMA and P7313SMA – Minimum of one and maximum of four are required	NA
	SMA cables – Minimum of two and maximum of four are required ²	NA

Table 5: Recommended power splitter for Transmitter non-linear distortion (with disturbing signal)

Power splitter	Model
PSPL5331 ³	5331-118

Installing the software

Follow the steps to download and install the latest Solution. See [Minimum system requirements](#) for compatibility.

1. Type the URL www.tek.com in the address bar of web browser and click Software Downloads
2. Enter **TekExpress Ethernet Tx Solution** in the *Enter your keywords* field, and click **Search**
3. Select the latest version of software and follow the instructions to download. Copy the executable file into the oscilloscope.

² For each lane of 2.5GBASE-T with disturbing signal, a pair of SMA cables to connect the disturbing signal generator output to the power splitter and a pair of short SMA cables to connect the fixture output (DUT signal) to the power splitter are required.

³ Total number of splitters used should be equal to twice the number of lanes (D+ and D-) to be tested (used for combining disturbing signal with DUT test mode signal).

Additional splitters are required for testing multilane with AFG or AWG:

- AFG: two splitters for testing every additional lanes.
- AWG: additional splitters depending on the number of lanes to be tested.


4. Double-click the executable and follow the on-screen instructions. The software is installed at
5. Select Application > TekExpress Ethernet NBASE-T from the TekScope menu to [launch the application](#).

View software version

Use the following instructions to view version information for the application and for the application modules such as the Programmatic Interface and the Programmatic Interface Client.

To view version information for , click  button in the TekExpress application and select **About TekExpress**.



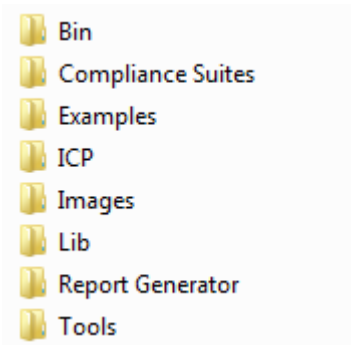
 **Note:** This example shows a typical Version Details dialog box, and may not reflect the actual values as shown when you open this item in the application.

Application directories

TekExpress Ethernet NBASE-T application

The TekExpress Ethernet NBASE-T application files are installed at the following location:

C:\Program Files\Tektronix\TekExpress\TekExpress Ethernet Tx



The following table lists the application directory names and their purpose.

Table 6: Application directories and usage

Directory names	Usage
Bin	Contains TekExpress Ethernet NBASE-T application libraries
Compliance Suites	Contains compliance-specific files
Examples	Contains various support files
ICP	Contains instrument and TekExpress Ethernet NBASE-T application-specific interface libraries

Table continued...

Directory names	Usage
Images	Contains images of the TekExpress Ethernet NBASE-T application
Lib	Contains utility files specific to the TekExpress Ethernet NBASE-T application
Report Generator	Contains style sheets for report generation
Tools	Contains instrument and TekExpress Ethernet NBASE-T application-specific files

See also

[View test-related files](#)

[File name extensions](#)

File name extensions

The application uses the following file name extensions:

File name extension	Description
.TekX	Application session files (the extensions may not be displayed)
.py	Python sequence file
.xml	Test-specific configuration information (encrypted) files Application log files
.wfm	Test waveform files
.mht	Test result reports (default) Test reports can also be saved in HTML format
.pdf	Test result reports Application help document
.xslt	Style sheet used to generate reports

See also

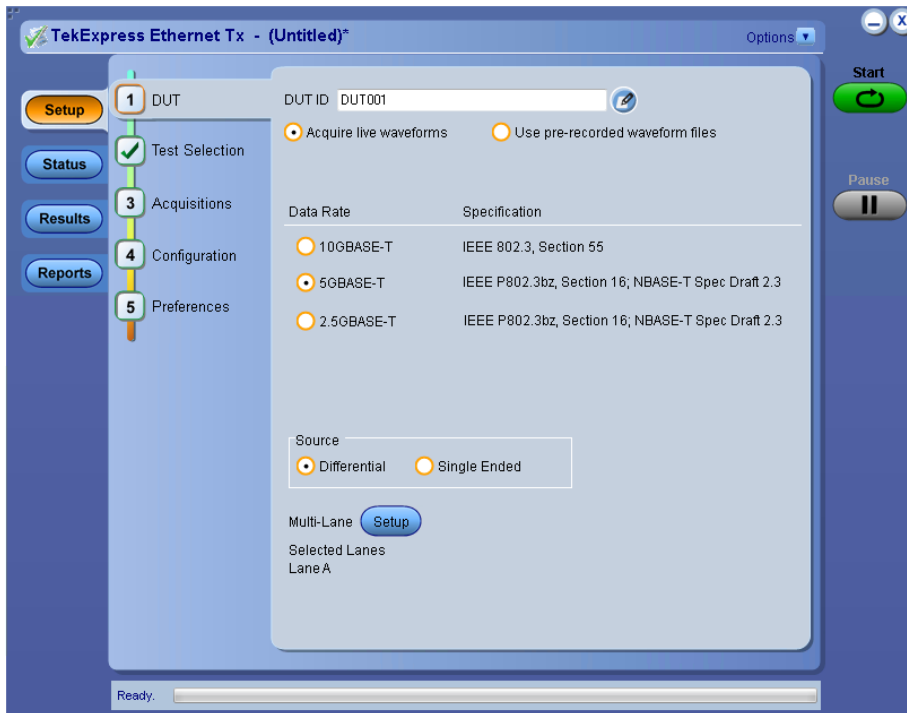
[View test-related files](#)

[Application directories](#)

Operating basics

Launch the application

To launch the TekExpress Ethernet Tx Solution, select **Application > TekExpress Ethernet Tx** from the TekScope menu.



When you launch the application for the first time, the file `C:\Users\<username>\My Documents\My TekExpress\Ethernet Tx\Resources.xml` is mapped to drive X:. This file contains information about available network-connected instruments. The session files are stored in `X:\Ethernet Tx\`. If this file is not found, then the application runs Instrument Discovery Program to detect the connected instruments before launching Ethernet NBASE-T Solution.

If the application goes behind the oscilloscope application, click **Application > Ethernet Tx** to bring it to the front. To keep the Ethernet Tx application window on top, select **Keep On Top** from the Ethernet Tx *Options menu*.

See also

[Application controls](#)

[Application panel overview](#)

Application panels overview

TekExpress Ethernet Tx Solution uses panels to group related configuration, test, and results settings. Click any button to open the associated panel. A panel may have one or more tabs that list the selections available in that panel. Controls in a panel can change depending on settings made in that panel or another panel

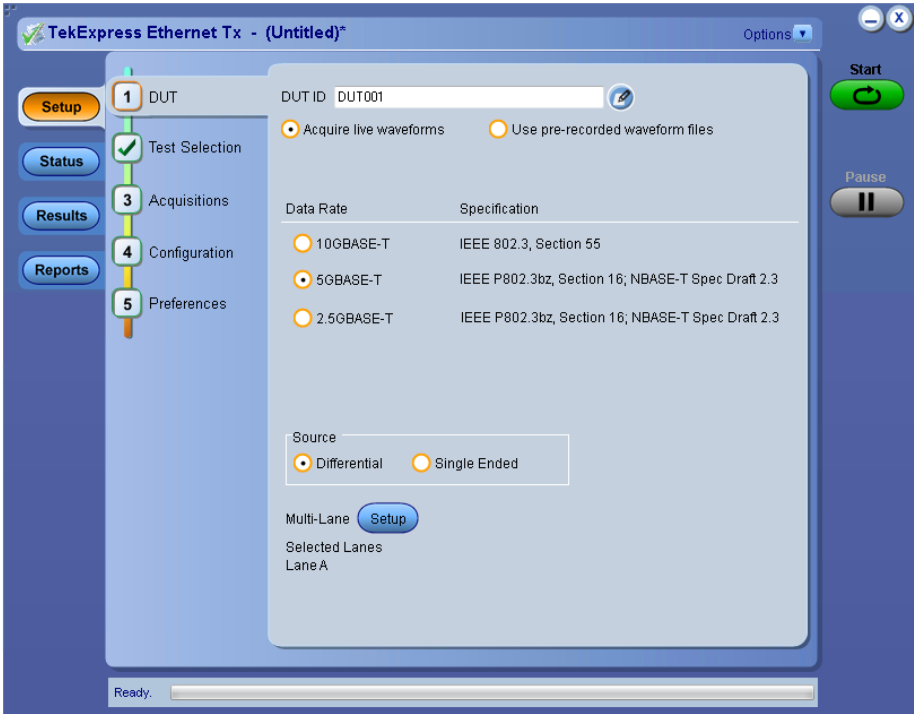


Table 7: Application panels overview

Panel Name	Purpose
Setup panel	<p>The Setup panel shows the test setup controls. Click the Setup button to open this panel.</p> <p>Use this panel to:</p> <ul style="list-style-type: none">• Set DUT tab parameters• Select tests• Set acquisition tab parameters• Set configuration tab parameters• Set preferences tab parameters
Status panel	<p>View the progress and analysis status of the selected tests, and view test logs.</p>
Results panel	<p>View a summary of test results and select result viewing preferences.</p>
Reports panel	<p>Browse for reports, save reports as specific file types, specify report naming conventions, select report content to include (such as summary information, detailed information, user comments, setup configuration, application configuration), and select report viewing options.</p>

See also









[Application controls](#)

Global application controls

Application controls

This section describes the application controls.


Table 8: Application controls description

Item	Description
<p><i>Options menu</i></p> 	Menu to display global application controls.
<p><i>Test Panel buttons</i></p> 	Controls that open panels for configuring test settings and options.
<p>Start / Stop button</p> 	<p>Use the Start button to start the test run of the measurements in the selected order. If prior acquired measurements are not cleared, then new measurements are added to the existing set.</p> <p>The button toggles to the Stop mode while tests are running. Use the Stop button to abort the test.</p>
<p>Pause / Continue button</p> 	Use the Pause button to temporarily pause the acquisition. When a test is paused, this button changes to "Continue."
<p>Clear button</p> 	Use the Clear button to clear all existing measurement results. Adding or deleting a measurement, or changing a configuration parameter of an existing measurement, also clears measurements. This is to prevent the accumulation of measurement statistics or sets of statistics that are not coherent. This button is available only on Results panel .
<p>Application window move icon</p> 	Place the cursor over the three-dot pattern in the upper left corner of the application window. When the cursor changes to a hand, drag the window to the desired location.
<p>Minimize icon</p> 	Click to minimize the application.
<p>Close icon</p> 	Click to close the application.

See also

[Application panel overview](#)

Options menu overview

To access Options menu, click  in the upper-right corner of the application. It has the following:

Default Test Setup
Open Test Setup
Save Test Setup
Save Test Setup As
Open Recent
Instrument Control Settings
Keep On Top
Email Settings
Deskew
Help
About TekExpress

Menu	Function
Default Test Setup	Opens an untitled test setup with defaults selected Acquire Live Waveforms Data Rate: 10GBASE-T Specification: IEEE 802.3, Section 55 Source: Differential Number of Lanes to Test: 1 Lane
Open Test Setup	Opens a saved test setup
Save Test Setup	Saves the current test setup
Save Test Setup As	Saves the current test setup with a different file name or file type
Open Recent	Displays the recently opened test setups to open
<i>Instrument Control Settings</i>	Detects, lists, and refreshes the connected instruments found on specified connections (LAN, GPIB, USB, and so on)
Keep On Top	Keeps the TekExpress Ethernet Tx application on top in the desktop
Table continued...	

Menu	Function
Email Settings	Use to configure email options for test run and results notifications
Deskew	Allows the user to deskew the probes
Help	Displays the TekExpress Ethernet Tx help
About TekExpress	<ul style="list-style-type: none"> Displays application details such as software name, version number, and copyright Provides a link to the end-user license agreement Provides a link to the Tektronix Web site

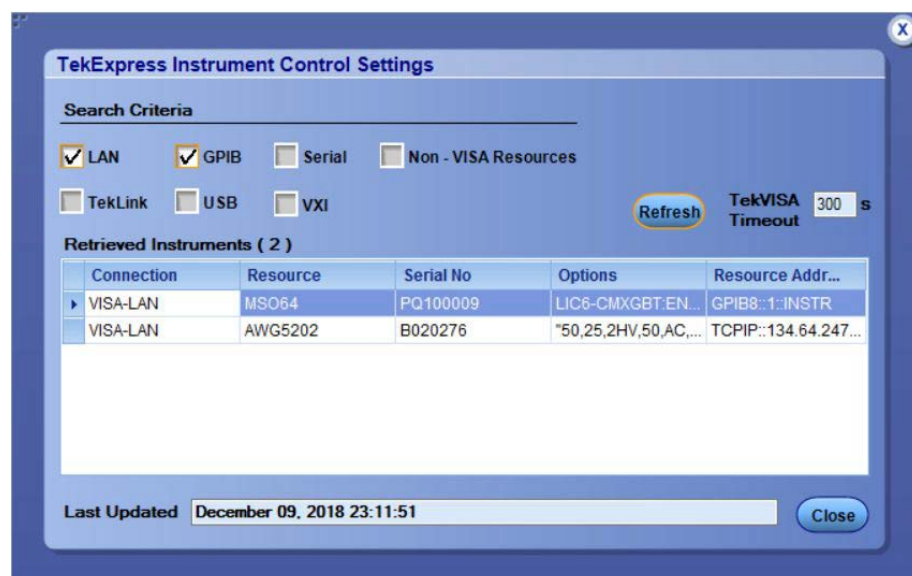
See also

[Application controls](#)

TekExpress instrument control settings

Use TekExpress Instrument Control Settings dialog box to search the instruments (resources) connected to the application. You can use the Search Criteria to search the connected instruments depending on the connection type. The details of the connected instrument is displayed in the Retrieved Instruments window.

You can access this dialog box from the **Options** menu.



The connected instruments displayed here can be selected for use under Global Settings in the test configuration section.




Note: Under **Instrument Control Settings**, select GPIB Option (Default setting), TekExpress Ethernet Tx when using application.

See also

[Options menu overview](#)

View connected instruments

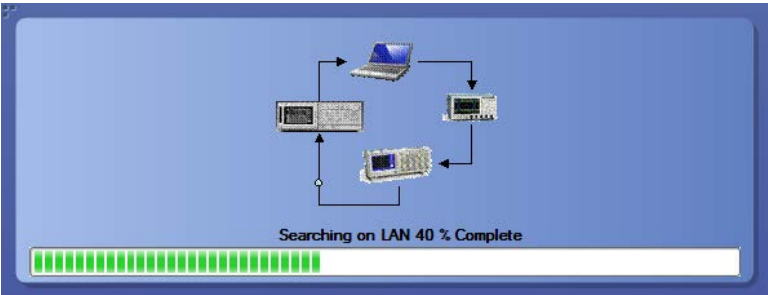
Use TekExpress Instrument Control Settings dialog box to search the instruments (resources) connected to the application. The application uses TekVISA to discover the connected instruments.

 **Note:** The correct instruments required for the test setup must be connected and recognized by the application before running the test.

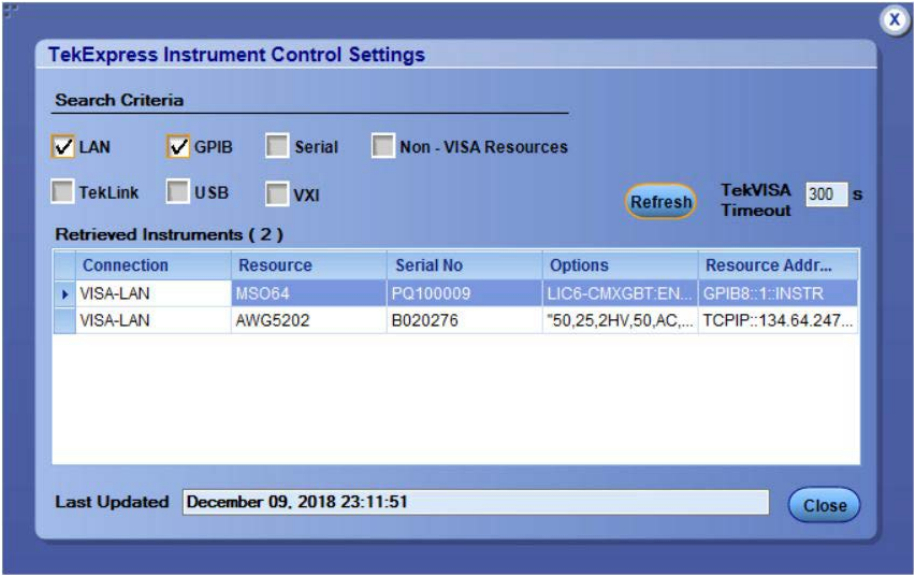
To refresh the list of connected instruments:

1. From the Options menu, select **Instrument Control Settings**.
2. In the **Search Criteria** section of the Instrument Control Settings dialog box, select the connection types of the instruments to search.

Instrument search is based on the VISA layer, but different connections determine the resource type, such as LAN, GPIB, and USB. For example, if you choose LAN, the search will include all the instruments supported by TekExpress that are communicating over the LAN.
3. Click **Refresh** TekExpress searches for connected instruments.



4. After searching, the dialog box lists the instrument-related details based on the search criteria. For example, For the Search Criteria as LAN and GPIB, the application displays all LAN and GPIB instruments connected to the application.



The details of the instruments are displayed in the Retrieved Instruments table. The time and date of instrument refresh is displayed in the Last Updated field.

Configure email settings

Use the Email Settings utility to get notified by email when a measurement completes, or produces any error condition. Follow the steps to configure email settings:

1. Select **Options > Email Settings** to open the Email Settings dialog box.
2. (Required) For Recipient email Address(es), enter one or more recipient email addresses. To include multiple addresses, separate the addresses with commas.
3. (Required) For Sender's Address, enter the email address used by the instrument. This address consists of the instrument name, followed by an underscore, followed by the instrument serial number, then the @ symbol, and the email server ID. For example: DSA8300_B130099@yourcompany.com.
4. (Required) In the Server Configuration section, type the SMTP Server address of the Mail server configured at the client location, and the SMTP Port number, in the corresponding fields.

If this server requires password authentication, enter a valid login name, password, and host name in the corresponding fields.



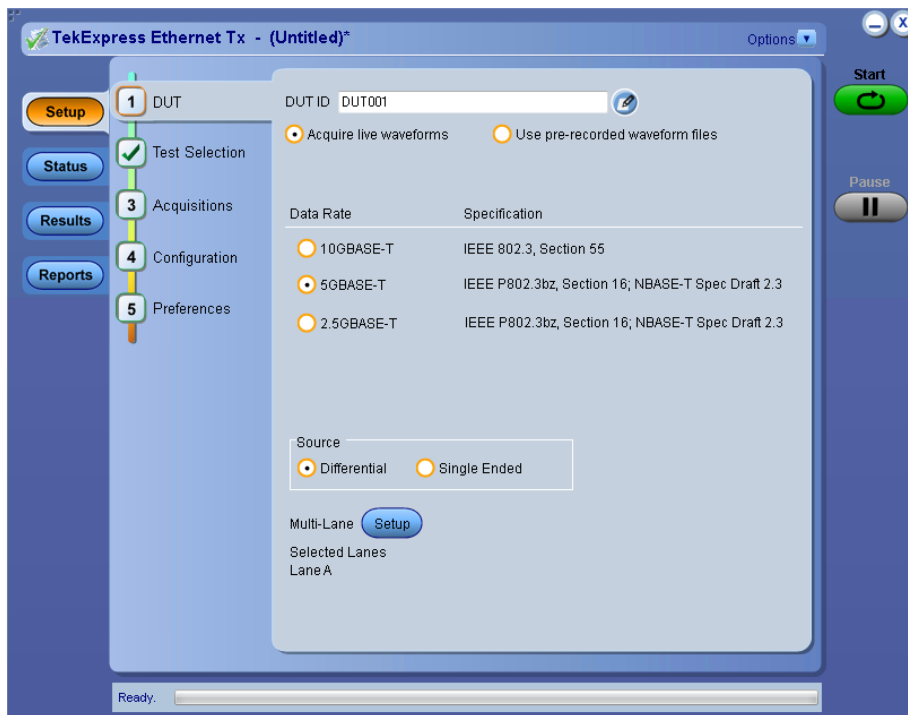
Note: If any of the above required fields are left blank, the settings will not be saved and email notifications will not be sent.

5. In the Email Attachments section, select from the following options:
 - **Reports:** Select to receive the test report with the notification email.
 - **Status Log:** Select to receive the test status log with the notification email. If you select this option, then also select whether you want to receive the full log or just the last 20 lines.
6. In the Email Configuration section:
 - Enter a maximum file size for the email message. Messages with attachments larger than this limit will not be sent. The default is 5 MB.
 - Enter the number in the Number of Attempts to Send field, to limit the number of attempts that the system makes to send a notification. The default is 1. You can also specify a timeout period.
7. Select the **Email Test Results When complete or on error** check box. Use this check box to quickly enable or disable email notifications.
8. To test your email settings, click **Test Email**.
9. To apply your settings, click **Apply**.
10. Click **Close** when finished.

Setup panel

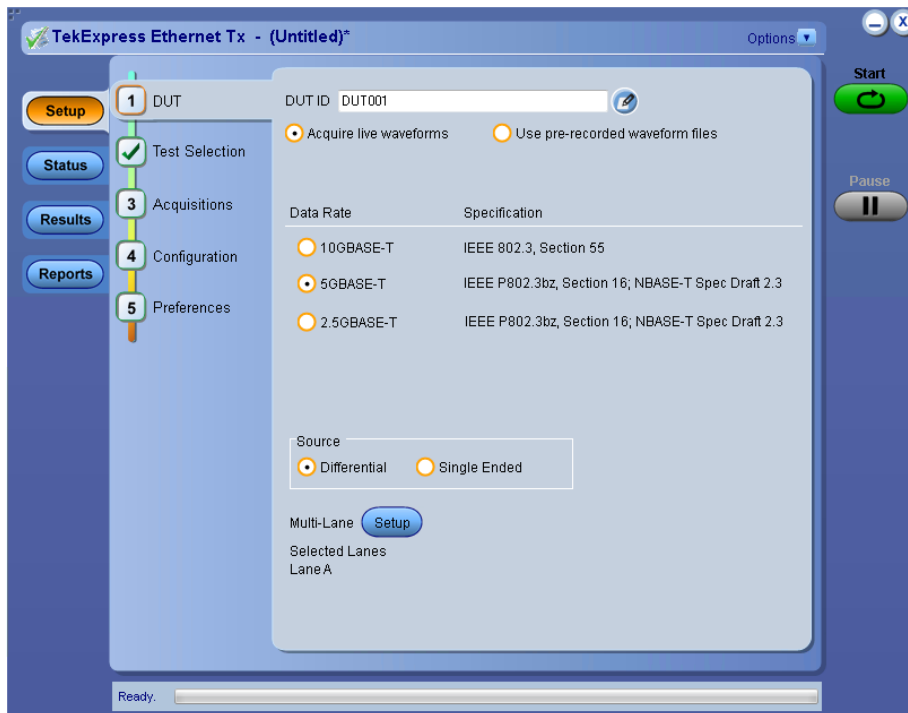
Setup panel overview

The Setup panel contains sequentially ordered tabs that help you guide through the test setup and execution process.




Set DUT parameters

Use the DUT tab to select parameters for the device under test. These settings are global and apply to all tests for the current session. DUT settings also affect the list of available tests in the Test Selection tab.



Click **Setup** > **DUT** to access the DUT parameters:

Table 9: DUT tab settings

Setting	Description
DUT ID	Adds an optional text label for the DUT to reports. The default value is DUT001. The maximum number of characters is 32. You cannot use the following characters in an ID name: (,.,,...,\,/:"? "<> *)
 Comments icon (to the right of the DUT ID field)	Opens a Comments dialog box in which to enter optional text to add to a report. Maximum size is 256 characters. To enable or disable comments appearing on the test report. See Select report options for details.
Acquire live waveforms	Perform analysis on live waveforms.
Use pre-recorded waveform files	Perform analysis on pre-recorded waveforms.
Data Rate	
10GBASE-T	Specification <ul style="list-style-type: none">IEEE 802.3, Section 55
5GBASE-T	Specification <ul style="list-style-type: none">IEEE P802.3bz, Section 16; NBASE-T Spec Draft 2.3
2.5GBASE-T	
Source	
Differential	Select the source as Differential
Single Ended	Select the source as Single Ended
Multi-Lane	Select the number of lanes to test.
Setup	Click to select the lanes to test.
Selected Test Lanes	Displays the selected lanes.

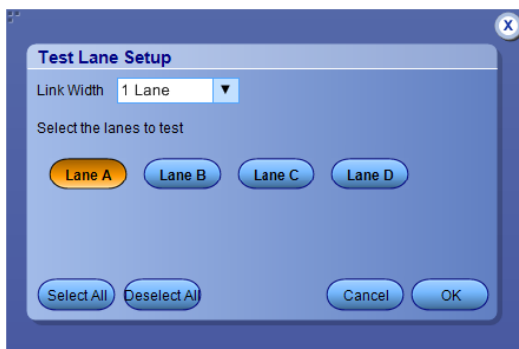


Figure 1: Test Lane Setup

See also[Select a test](#)

Select tests

Use the Test Selection tab to select the tests.

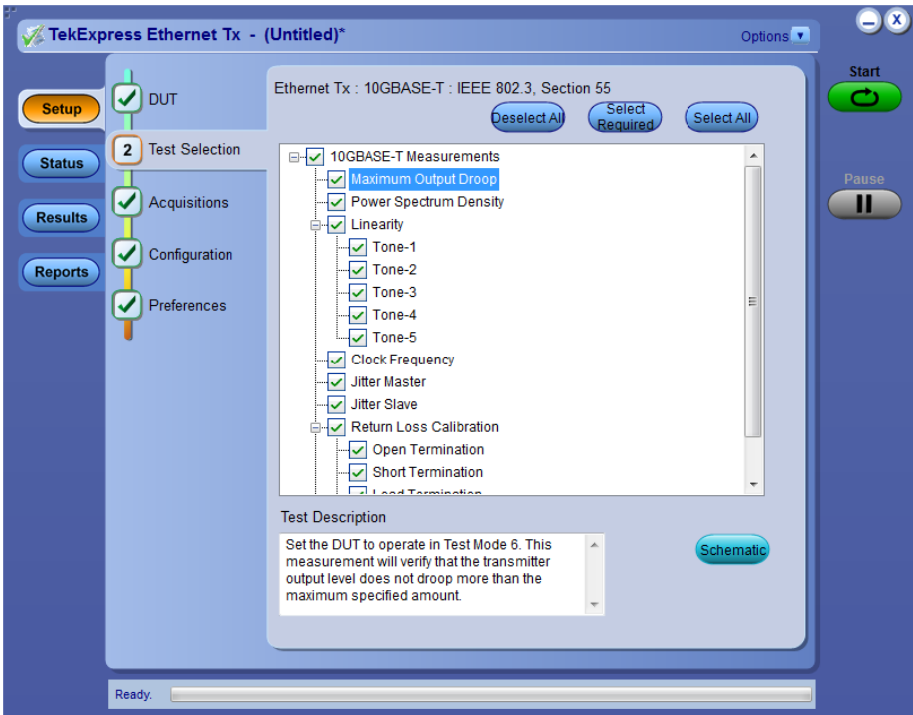


Table 10: Test Selection tab settings

Setting	Description
Tests	Click on a test to select or unselect. Highlight a test to show details in the Test Description pane.
Test Description	Shows a brief description of the highlighted test in the Test field.

See also

[Set acquisition tab parameters](#)

Set acquisition tab parameters

Use the Acquisitions tab to view test acquisition parameters. The contents displayed on this tab depends on the DUT type and the tests selected.

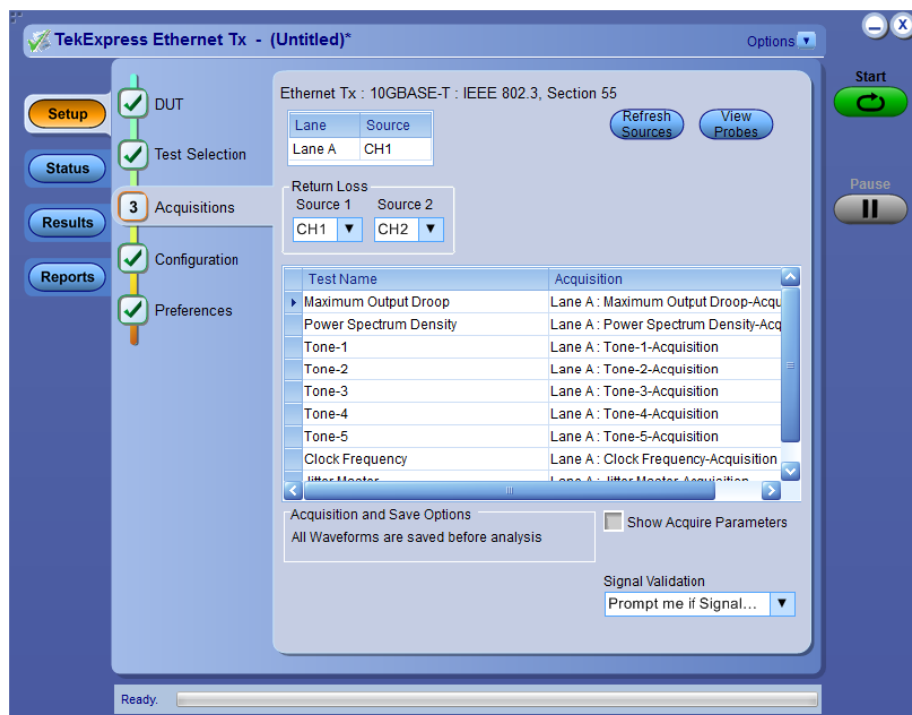
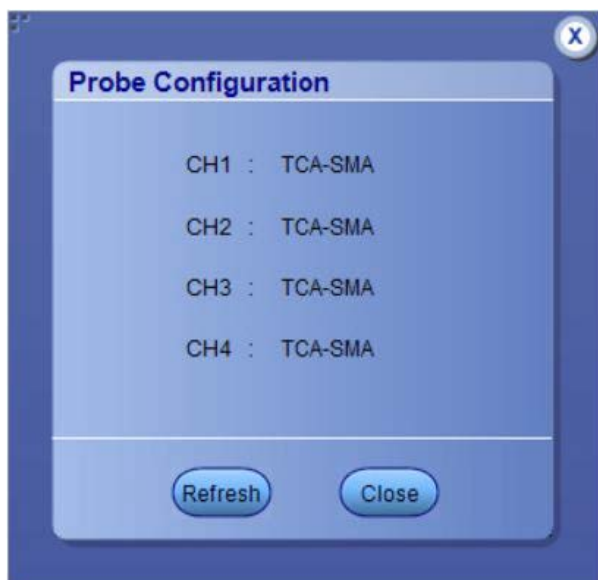


Table 11: Acquisitions tab settings

Setting	Description
View Probes	Click to view the probe configuration
Show Acquire Parameters	Select to view the acquisition parameters.
Signal Validation	Select the signal validation type <ul style="list-style-type: none"> Prompt me if Signal Validation Fails Skip test if Signal Validation Fails Use signal as is - Don't Validate



TekExpress saves all acquisition waveforms to files by default. Waveforms are saved in a unique folder for each session (a session starts when you click the Start button). The folder path is X:\Ethernet Tx\Untitled Session\<dutid>\<date>_<time>. Images created for each analysis, CSV files with result values, reports, and other information specific to that particular execution are also saved in this folder.

Saving a session moves the session file contents from the Untitled Session folder to the specified folder name, and changes the session name to the specified name.

Set configuration tab parameters

Use the Configuration tab to view the instruments detected (Global Settings).

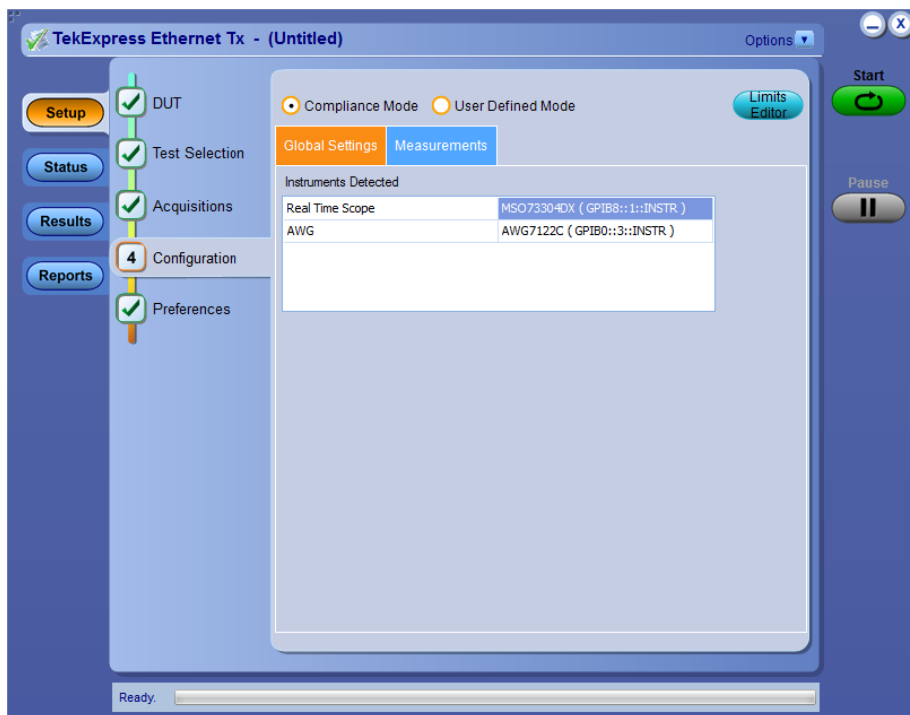


Figure 2: Configuration tab: Global Settings

Table 12: Configuration tab settings


Setting		Description
Compliance Mode		Select to view compliance mode. By default Compliance Mode is selected.
User Defined Mode		Select to view user defined mode
Global Settings		
Instruments Detected		<p>Displays the instruments connected to this application. Click on the instrument name to open a list of available (detected) instruments.</p> <p>Select Options > Instrument Control Settings and click Refresh to update the instrument list.</p> <p> Note: Verify that the GPIB search criteria (default setting) in the Instrument Control Settings is selected when using Ethernet Tx application.</p>
Measurements		
Maximum Output Droop	Acquire	Population
	Analyze	Ref Level Mid Level Hysteresis Start Time End Time
Power Spectrum Density	Acquire	Acquisition Average
	Analyze	Start Frequency Stop Frequency Resolution Bandwidth Power Level Start Frequency Power Level Stop Frequency Smoothing Average

Table continued...

Setting		Description
Tone-1	Acquire	Acquisition Average With disturbing signal (45 MHz) ⁴ Compensation⁴ Combiner Effect Compensation Value Auto Compensate
	Analyze	Start Frequency Stop Frequency Resolution Bandwidth Apply Filter
Tone-2	Acquire	Acquisition Average With disturbing signal (45 MHz) ⁴ Compensation⁴ Combiner Effect Compensation Value Auto Compensate
	Analyze	Start Frequency Stop Frequency Resolution Bandwidth Apply Filter
Tone-3	Acquire	Acquisition Average With disturbing signal (45 MHz) ⁴ Compensation⁴ Combiner Effect Compensation Value Auto Compensate
	Analyze	Start Frequency Stop Frequency Resolution Bandwidth Apply Filter
Table continued...		

⁴ This configuration is available for 2.5GBASE-T data rate only.

Setting		Description
Tone-4	Acquire	Acquisition Average With disturbing signal (45 MHz) ⁴ Compensation⁴ Combiner Effect Compensation Value Auto Compensate
	Analyze	Start Frequency Stop Frequency Resolution Bandwidth Apply Filter
Tone-5	Acquire	Acquisition Average With disturbing signal (45 MHz) ⁴ Compensation⁴ Combiner Effect Compensation Value Auto Compensate
	Analyze	Start Frequency Stop Frequency Resolution Bandwidth Apply Filter
Clock Frequency	Acquire	Population
	Analyze	Ref Level Mid Level Hysteresis
Jitter Master	Acquire	Acquisition Duration
	Analyze	Ref Level Mid Level Hysteresis

Table continued...

Setting		Description
Jitter Slave	Acquire	Acquisition Duration
	Analyze	Ref Level Mid Level Hysteresis
Open Termination	Acquire	Acquisition Average
	Analyze	Smoothing Average Calibration files path
Short Termination	Acquire	Acquisition Average
	Analyze	Smoothing Average Calibration files path
Load Termination	Acquire	Acquisition Average
	Analyze	Smoothing Average Calibration files path
Return Loss	Acquire	Acquisition Average
	Analyze	Smoothing Average Calibration files path

Population Specifies a limit to the amount of waveform data that is analyzed

Ref Level. Absolute Use to manually set the reference levels.

Percentage Use to set the reference levels as a percentage.

Mid Level. A reference voltage level that defines when the waveform state transition occurs at a given threshold.

Hysteresis. Used to prevent small amounts of noise in a waveform from producing multiple threshold crossings. Use when the rising and falling thresholds for a given reference voltage level are set to the same value.

Start Time. Specifies the Droop measurement start time (Time from the zero crossing).

End Time. Specifies the Droop measurement end time (Time from the zero crossing).

Acquisition Average. Specifies the number of waveforms over which averaging is done.

Start Frequency. Specifies the PSD curve start frequency.

Stop Frequency. Specifies the PSD curve stop frequency.

Resolution Bandwidth. Determines the smallest frequency difference that can be resolved in the frequency domain output data.

Power Level Start Frequency. Specifies the power level start frequency.

Power Level Stop Frequency. Specifies the power level stop frequency.

Smoothing Average. Specifies the window size in terms of number of samples used for smoothing.

Acquisition Duration. Specifies the waveform acquired time.

Apply Filter. Applies a time domain Low-pass filter when checked with the cutoff frequency (10G: 400MHz, 5G: 200MHz, 2.5G: 100MHz).

Set preferences tab parameters

Use the Preferences tab to set the application action on completion of a measurement.

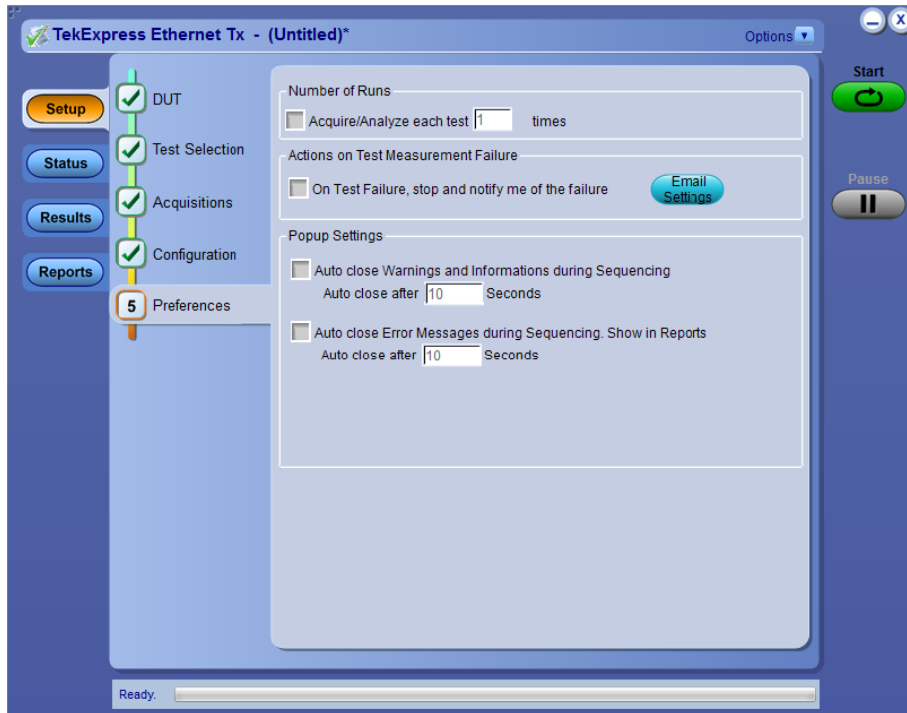


Table 13: Preferences tab settings

Setting	Description
Number of Runs	
Acquire/Analyze each test <no> times (not applicable to Custom Tests)	Select to repeat the test run by setting the number of times. By default, it is selected with 1 run.
Actions on Test Measurement Failure	
On Test Failure, stop and notify me of the failure	Select to stop the test run on Test Failure, and to get notified via email. By default, it is unselected. Click Email Settings to configure.
Popup Settings	
Auto close Warnings and Informations during Sequencing Auto close after <no> Seconds	Select to auto close warnings/informations during sequencing. Set the Auto close time. By default it is unselected.

Table continued...

Setting	Description
Auto close Error Messages during Sequencing. Show in Reports	Select to auto close Error Messages during Sequencing. Set the Auto close time. By default it is unselected.
Auto close after <no> Seconds	

Status panel overview

The Status button accesses the Test Status and Log View tabs, which provide status on test acquisition and analysis (Test Status tab) and a listing of test tasks performed (Log View tab). The application opens the Test Status tab when you start a test run. You can select the Test Status or the Log View tab to view these items while tests are running.

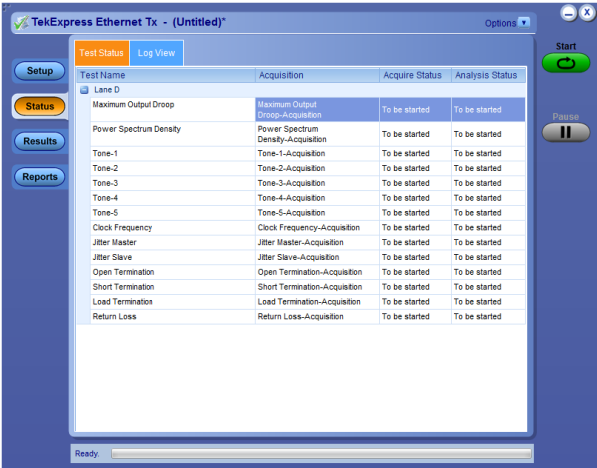


Figure 3: Test status view

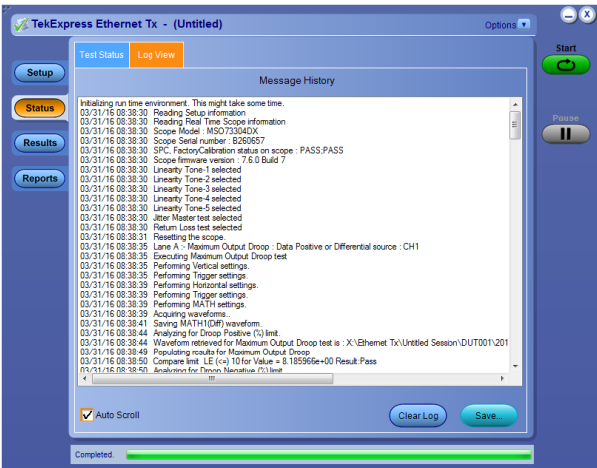


Figure 4: Log view

Table 14: Status panel Log View controls

Control	Description
Message History	Lists all executed test operations and timestamp information.
Table continued...	

Control	Description
Auto Scroll	Enables automatic scrolling of the log view as information is added to the log during the test.
Clear Log	Clears all messages from the log view.
Save	Saves the log file to a text file. Use the standard Save File window to navigate to and specify the folder and file name to which to save the log text.

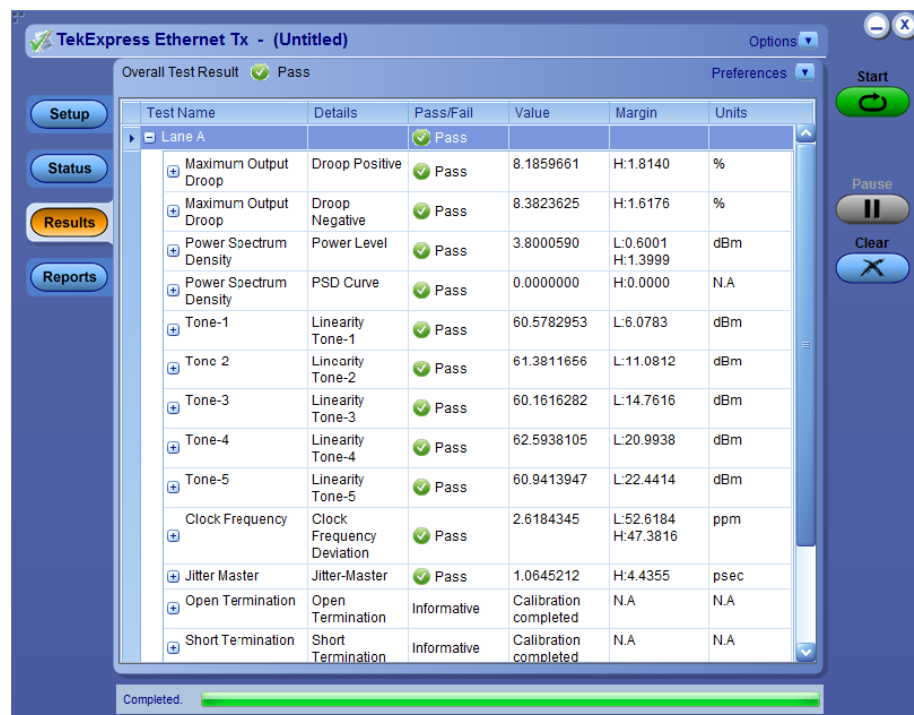
See also

[Application panel overview](#)

Results panel

Results panel overview

When a test finishes, the application automatically opens the **Results** panel to display a summary of test results.



See also

[View a report](#)

[Application panels overview](#)

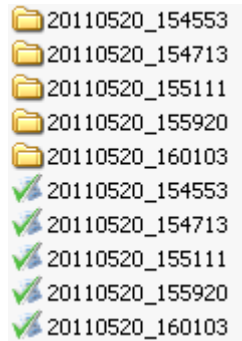
View test-related files

Files related to tests are stored in . Each test setup in this folder has both a test setup *file* and a test setup *folder*, both with the test setup name.

The test setup file is preceded by the TekExpress icon and usually has no visible file name extension.

Inside the test setup folder is another folder named for the DUT ID used in the test sessions. The default is DUT001.

Inside the DUT001 folder are the session folders and files. Each session also has a folder and file pair, both named for the test session using the naming convention (date)_(time). Each session file is stored outside its matching session folder:



Each session folder contains image files of any plots generated from running the test session. If you selected to save all waveforms or ran tests using prerecorded waveform files, these are included here.

The first time you run a new, unsaved session, the session files are stored in the `Untitled Session` folder located at `\My TekExpress\Ethernet Tx\`. When you name and save the session, the files are placed in a folder with the name that you specify. A copy of the test files stay in the `Untitled Session` folder until you run a new test or until you close the application.

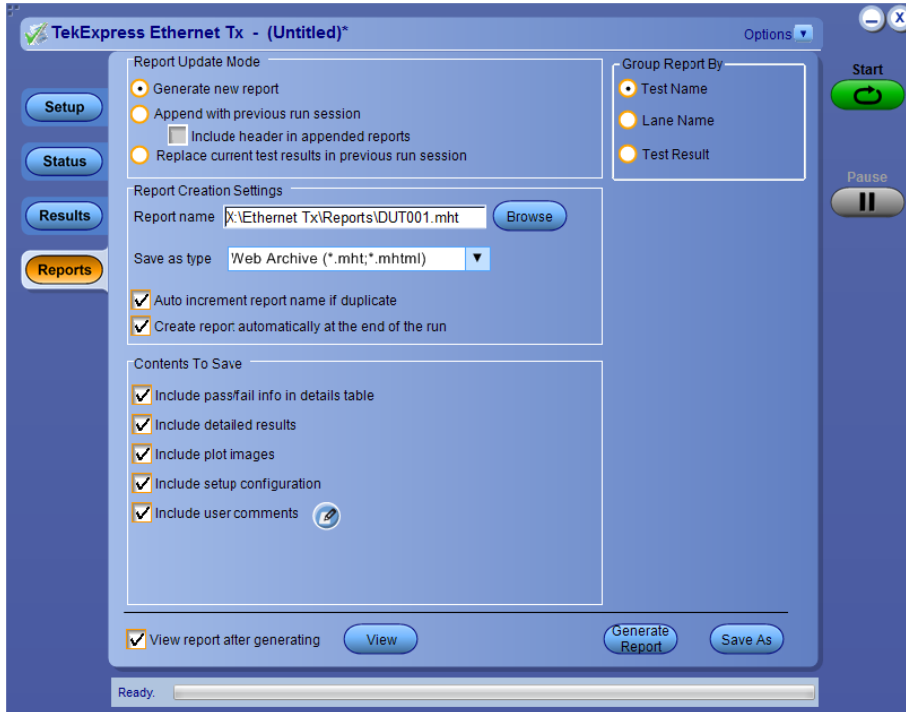
See also

[File name extensions](#)

Reports panel

Reports panel overview

Use the Reports panel to browse for reports, name and save reports, select test content to include in reports, and select report viewing options.



For information on setting up reports, see [Select report options](#). For information on viewing reports, see [View a report](#).

See also

[Applications panel overview](#)

Select report options



Click the **Reports** button and use the Reports panel controls to select which test result information to include in the report, and the naming conventions to use for the report. For example, always give the report a unique name or select to have the same name increment each time you run a particular test.

Select report options before running a test or when creating and saving test setups. Report settings are included in saved test setups.

In the Reports panel, select from the following report options:

Table 15: Report options

Setting	Description
Report Update Mode	
Generate new report	Creates a new report. The report can be in either .mht or .pdf file formats.
Append with previous run session	Appends the latest test results to the end of the current test results report.
Replace current test in previous run session	Replaces the previous test results with the latest test results. Results from newly added tests are appended to the end of the report.
Report Creation Settings	
Table continued...	

Setting	Description
Report name	<p>Displays the name and location from which to open a report. The default location is at \My TekExpress\Ethernet Tx\Untitled . The report file in this folder gets overwritten each time you run a test unless you specify a unique name or select to auto increment the report name.</p> <p>Change the report name or location.</p> <p>Do one of the following:</p> <ul style="list-style-type: none"> In the Report Path field, type over the current folder path and name. Double-click in the Report Path field and then make selections from the popup keyboard and click the Enter button. <p>Be sure to include the entire folder path, the file name, and the file extension. For example: C:\Documents and Settings\your user name\My Documents\My TekExpress\Ethernet Tx\DUT001.mht.</p> <p> Note: You cannot set the file location using the Browse button.</p> <p>Open an existing report.</p> <p>Click Browse, locate and select the report file and then click View at the bottom of the panel.</p>
Save as type	<p>Saves a report in the specified file type, selected from the drop-down list.</p> <p> Note: If you select a file type different from the default, be sure to change the report file name extension in the Report Name field to match.</p>
Auto increment report name if duplicate	Sets the application to automatically increment the name of the report file if the application finds a file with the same name as the one being generated. For example: DUT001, DUT002, DUT003. This option is enabled by default.
Create report automatically at the end of the run	Creates report at the end of the run.
Contents To Save	
Include pass/fail info in details table	Includes pass/fail info in the details table of the report.
Include detailed results	Includes detailed results in the report.
Include plot images	Includes plot images in the report.
Include setup configuration	Sets the application to include hardware and software information in the summary box at the top of the report. Information includes: the oscilloscope model and serial number, the oscilloscope firmware version, and software versions for applications used in the measurements.
Include complete application configuration	Includes complete application configuration in the report.
Include user comments	Select to include any comments about the test that you or another user added in the DUT tab of the Setup panel. Comments appear in the Comments section, under the summary box at the beginning of each report.
Table continued...	

Setting	Description
Group Report By	
Test Name	Select to group the tests in the report by test name.
Test Result	Select to group the tests in the report by test results
View report after generating	Automatically opens the report in a Web browser when the test completes. This option is selected by default.
View	Click to view the most current report.
Generate Report	Generates a new report based on the current analysis results.
Save As	Specify a name for the report.

View a report


The application automatically generates a report when test analysis is completed and displays the report in your default Web browser (unless you cleared the **View Report After Generating** check box in the Reports panel before running the test). If you cleared this check box, or to view a different test report, do the following:

1. Click the **Reports** button.
2. Click the **Browse** button and locate and select the report file to view.
3. In the Reports panel, click **View**.

For information on changing the file type, file name, and other report options, see [Select report options](#).

Report contents

A report shows detailed results and plots, as set in the Reports panel.



TekExpress Ethernet Tx

10GBASE-T Test Report

Setup Information			
DUT ID	DUT001	Scope Information	MSO73304DX, B260657
Date/Time	2016-03-31 08:38:30	SPC, FactoryCalibration	PASS:PASS
Device Type	Ethernet Tx	Scope F/W Version	7.6.0 Build 7
TekExpress Ethernet Tx Version	1.0.0.143	Channel1 Probe	P7330, B025431
TekExpress Framework Version	4.0.6.266	Return-Loss Probe1	P7330, B025431
Execution Mode	Live	Return-Loss Probe2	P7330, B025531
Probing Type	Differential		
Compliance Mode	True		
Overall Test Result	Pass		
Overall Execution Time	0:11:51		
DUT COMMENT:	General comment		

Test Name Summary Table	
Maximum Output Droop	Pass
Power Spectrum Density	Pass
Tone-1	Pass
Tone-2	Pass
Tone-3	Pass
Tone-4	Pass
Tone-5	Pass
Clock Frequency	Pass
Jitter Master	Pass
Open Termination	Pass
Short Termination	Pass
Load Termination	Pass
Return Loss	Pass

Setup configuration information:

The summary box at the beginning of the report lists setup configuration information. This information includes the oscilloscope model and serial number, optical module model and serial number, and software version numbers of all associated applications.

To exclude this information from a report, clear the **Include Setup Configuration** check box in the Reports panel before running the test.

User comments:

If you selected to include comments in the test report, any comments you added in the DUT tab are shown at the top of the report.

See also

[Results panel overview](#)

[View test-related files](#)

Running tests

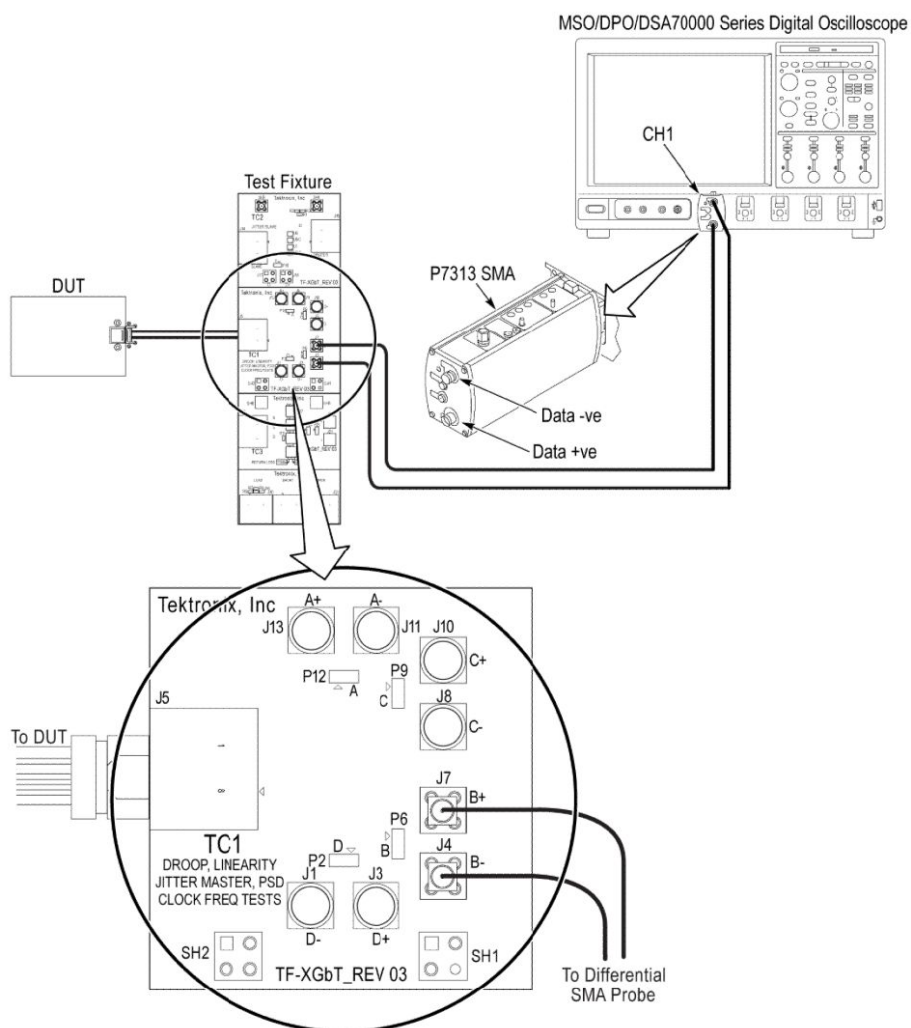
Equipment connection setup

Click **Setup** > **Test Selection** > **Schematic** to view the equipment setup diagram(s).

SMA Probe (Differential Source)

This section describes the equipment connection setup to perform Differential Source (SMA Probe) Calibration. (For details, see [Minimum system requirements](#)).

Equipment connection setup - Differential Source (SMA Probe) applies to all tests except Jitter-Slave, Return Loss and [Transmitter non-linear distortion \(with disturbing signal\)](#).



Note: When using high input impedance differential probe, ensure that each of the single ended lanes is terminated with 50 Ω .

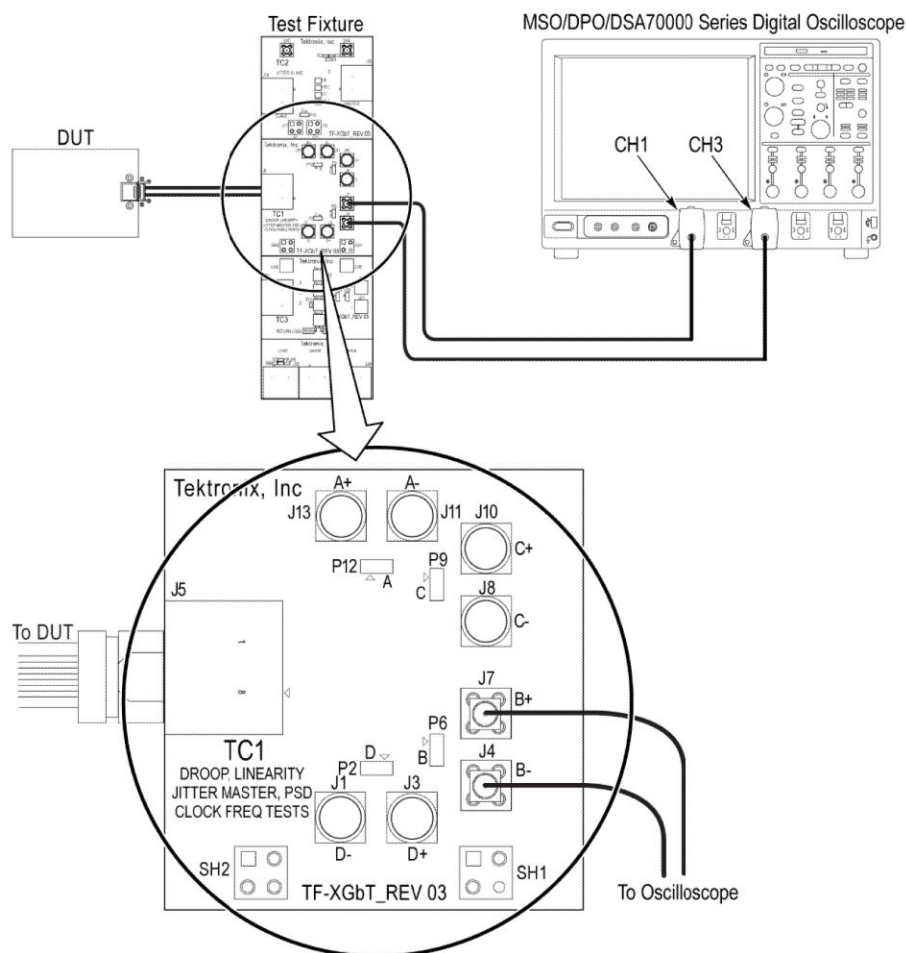
1253-008

Figure 5: SMA Probe (Differential Source)

SMA Cable (Single-Ended Source)

This section describes the equipments required and the connection setup to perform Single-Ended Source Calibration. (For details, see [Minimum system requirements](#)).

Equipment connection setup - Single-Ended Source (SMA Cable) applies to all tests except Jitter-Slave, Return Loss and [Transmitter non-linear distortion \(with disturbing signal\)](#).



Note: When using high input impedance differential probe, ensure that each of the single ended lanes is terminated with 50 Ω .

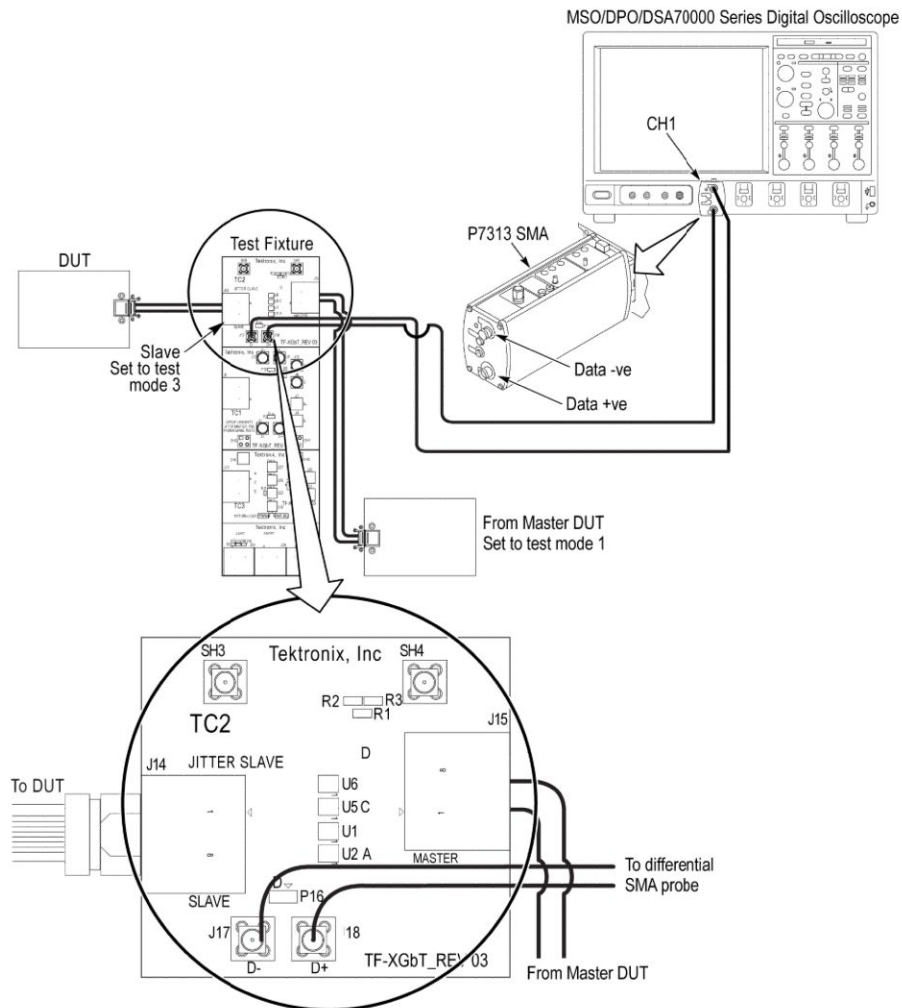
1253-009

Figure 6: SMA Cable (Single-Ended Source)

Jitter-Slave SMA Probe (Differential Source)

This section describes the equipments required and the connection setup to perform Jitter-Slave (Differential Source) Calibration. (For details, see [Minimum system requirements](#)).

Equipment connection setup - Jitter-Slave SMA Probe (Differential Source) applies to Jitter-Slave measurement.



Note: When using high input impedance differential probe, ensure that each of the single ended lanes is terminated with 50 Ω .

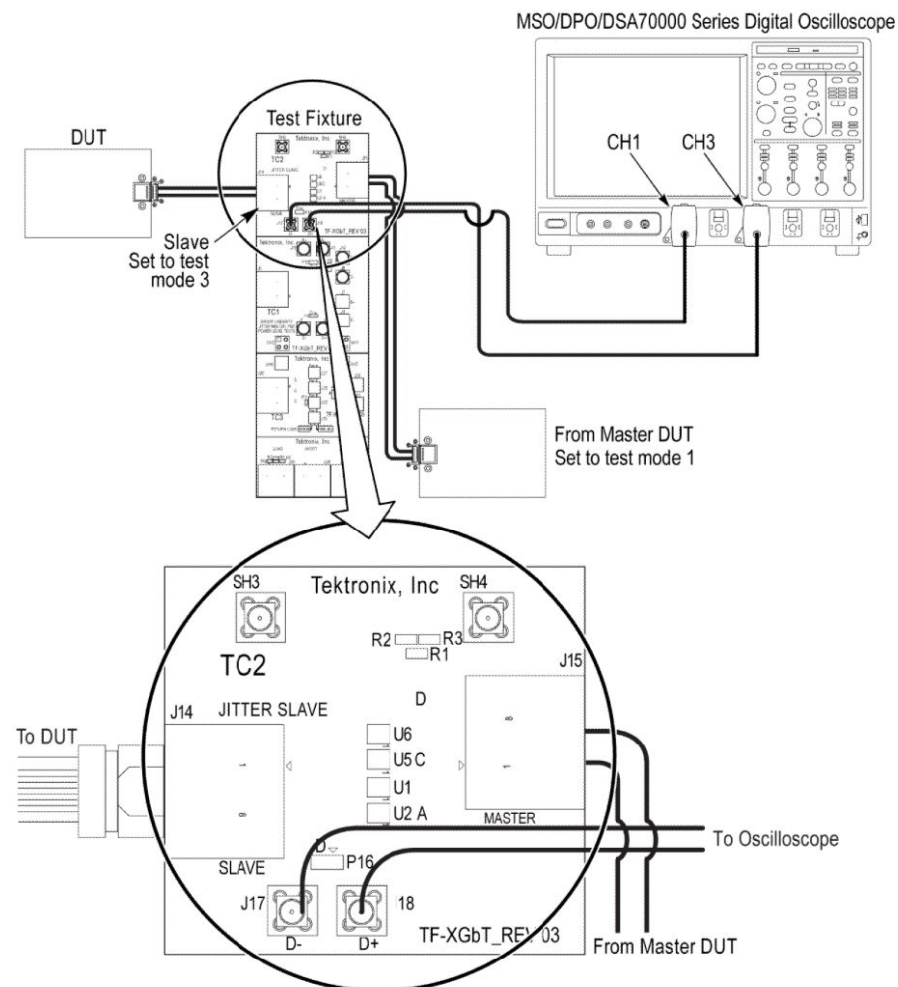
1253-010

Figure 7: Jitter-Slave SMA Probe (Differential Source)

Jitter-Slave SMA Cable (Single-Ended Source)

This section describes the equipments required and the connection setup to perform Jitter-Slave (Single-Ended Source) calibration. (For details, see [Minimum system requirements](#)).

Equipment connection setup - Jitter-Slave SMA Probe (Single-Ended Source) applies to Jitter-Slave measurement.



Note: When using high input impedance differential probe, ensure that each of the single ended lanes is terminated with 50 Ω .

1253-011

Figure 8: Jitter-Slave SMA Cable (Single-Ended Source)

Return Loss Calibration

This section describes the equipments required and the connection setup to perform Return Loss Calibration. (For details, see [Minimum system requirements](#)).

Equipment connection setup - Return Loss Calibration applies to Open Termination, Short Termination and Load Termination measurement.

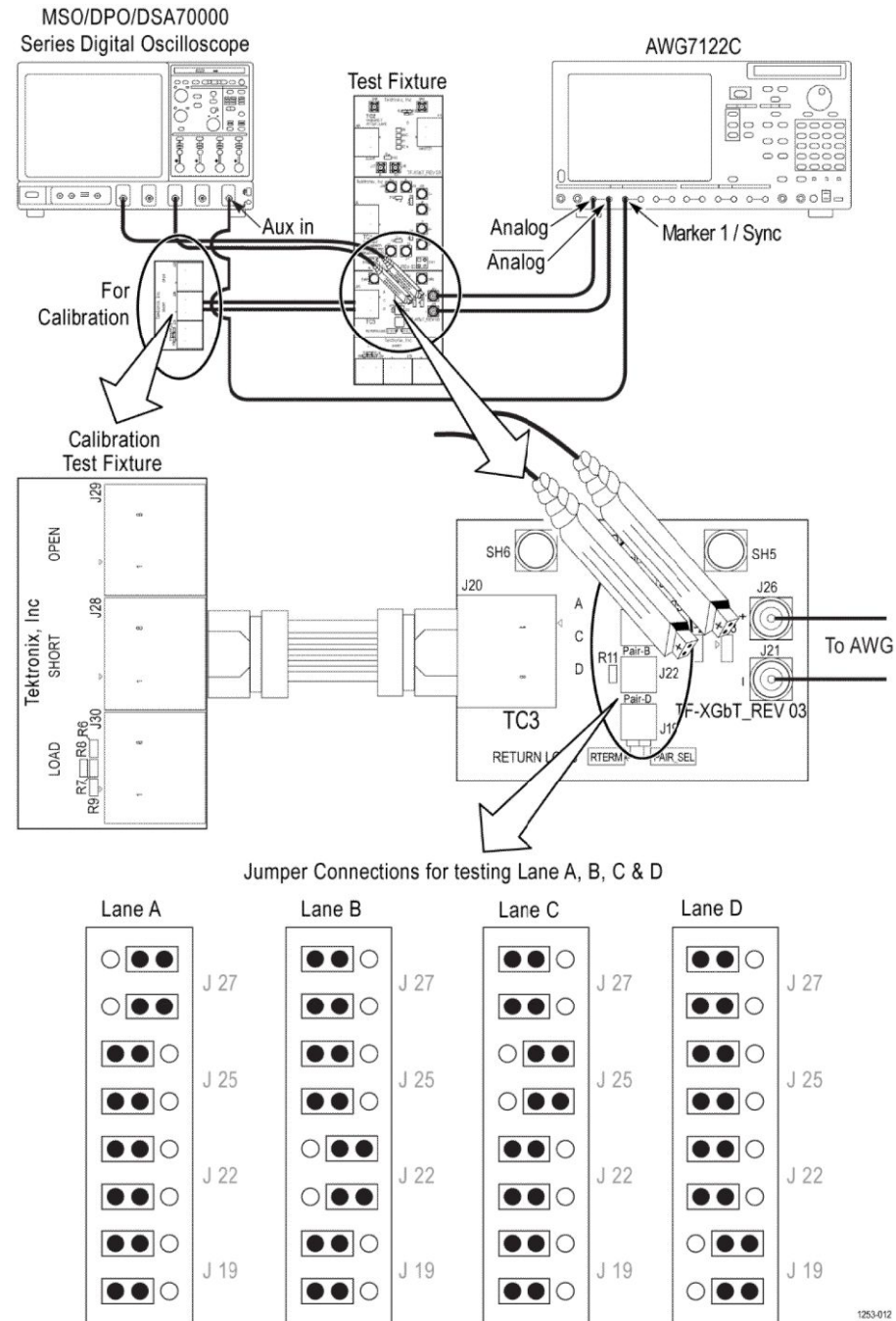


Figure 9: Return Loss Calibration - Open Termination

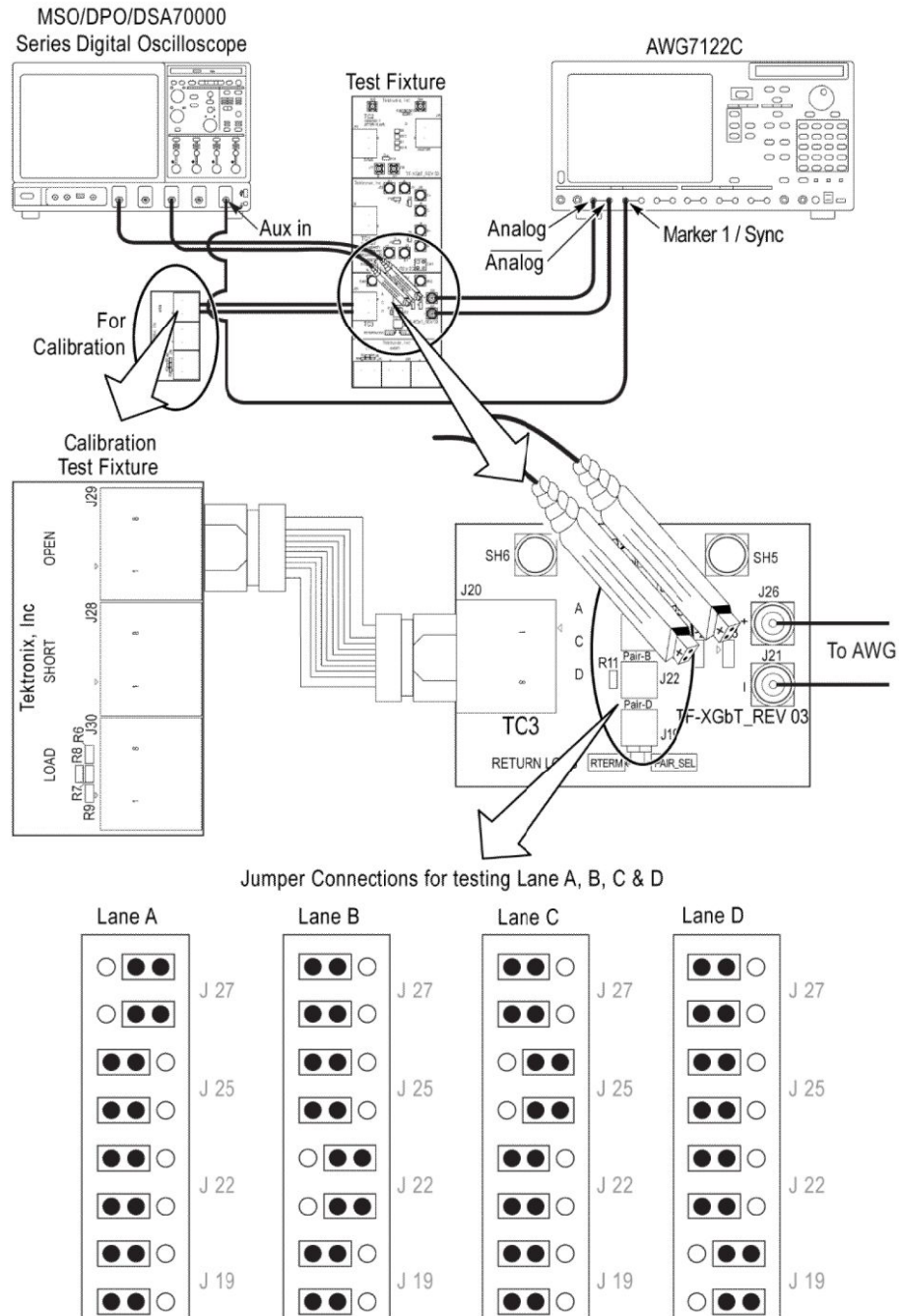


Figure 10: Return Loss Calibration - Short Termination



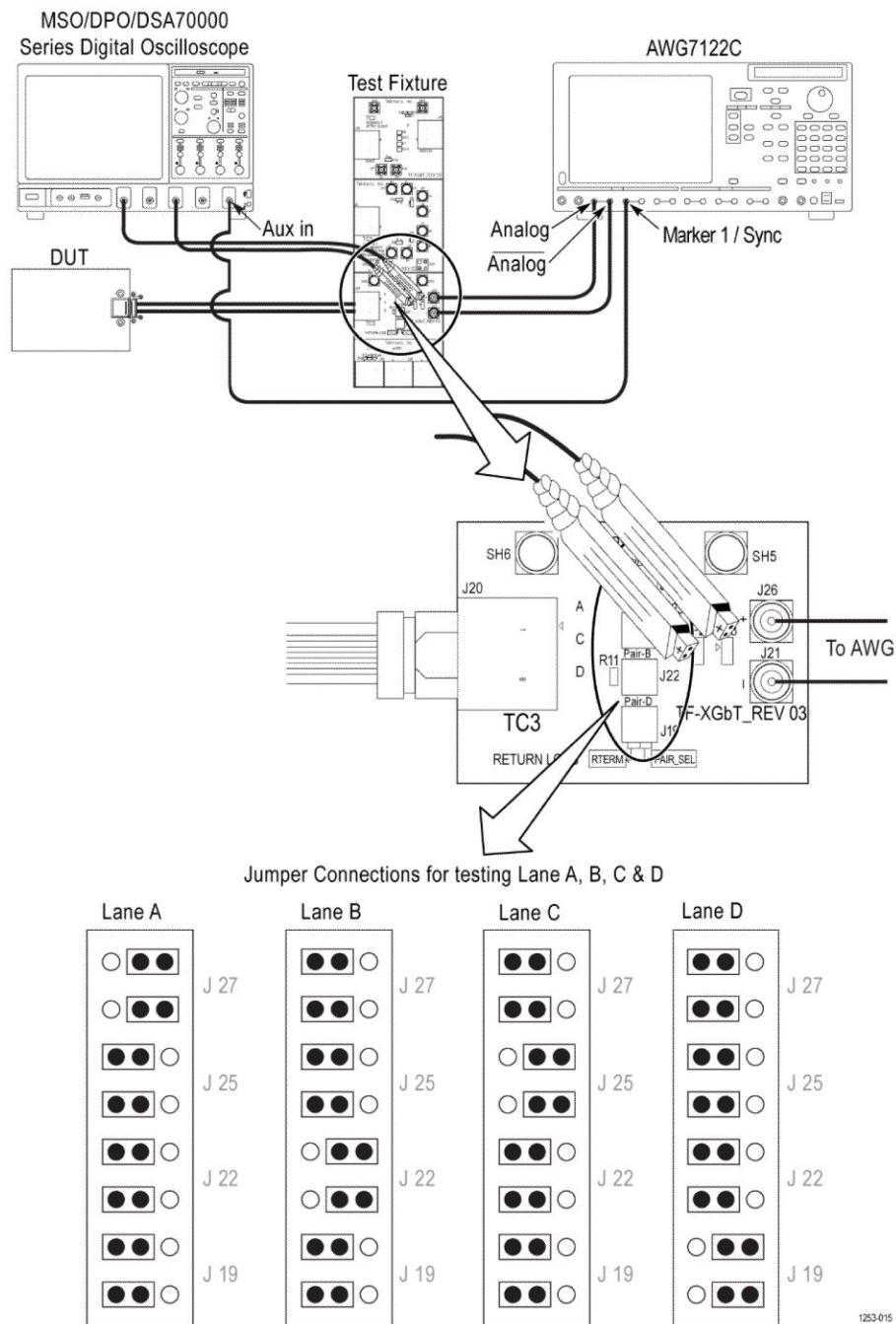
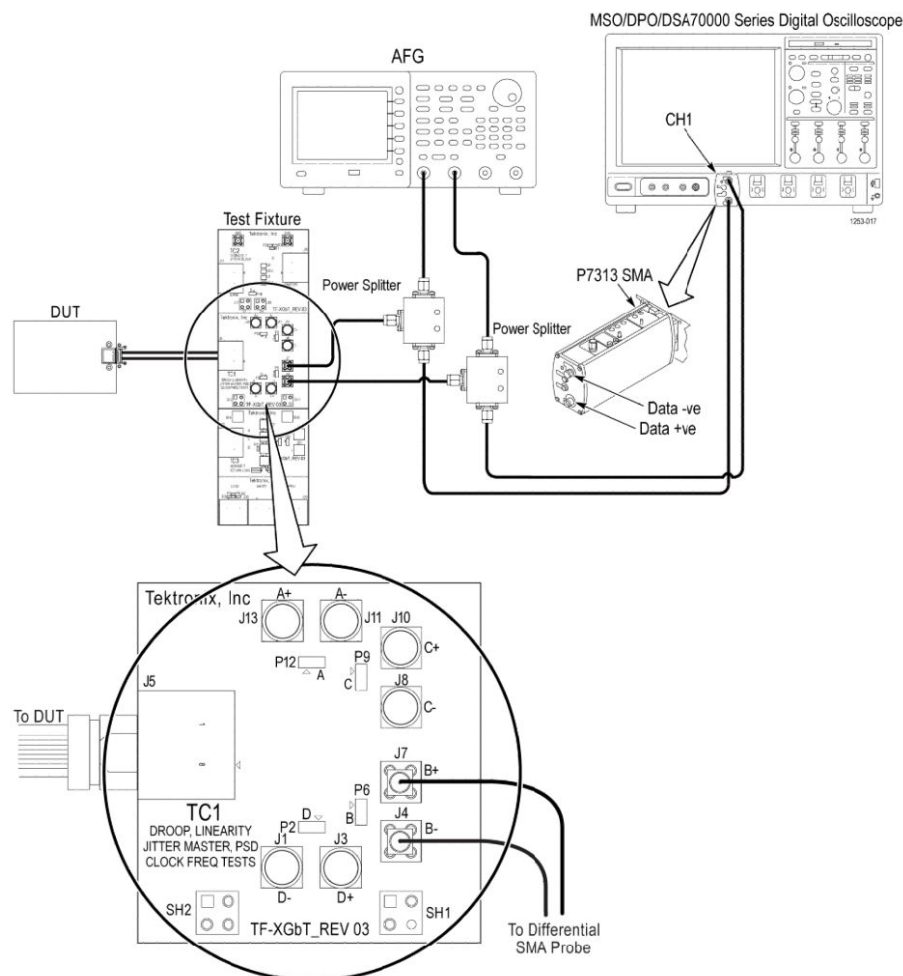


Figure 12: Return Loss Setup

Transmitter non-linear distortion with disturbing signal (Differential Source)

This section describes the equipments required and the connection setup to perform Transmitter non-linear distortion with disturbing signal (Differential Source). (For details, see [Minimum system requirements](#)).



Note: When using high input impedance differential probe, ensure that each of the single ended lanes is terminated with $50\ \Omega$.

Figure 13: Transmitter non-linear distortion with disturbing signal (Differential Source)



Note: Total number of splitters used should be equal to twice the number of lanes (D+ and D-) to be tested (used for combining disturbing signal with DUT test mode signal).



Note: Additional splitters are required for testing multilane with AFG or AWG:

- AFG: two splitters for testing every additional lanes.
- AWG: additional splitters depending on the number of lanes to be tested.

Transmitter non-linear distortion with disturbing signal (Single-Ended)

This section describes the equipments required and the connection setup to perform Transmitter non-linear distortion with disturbing signal (Single-Ended). (For details, see [Minimum system requirements](#)).

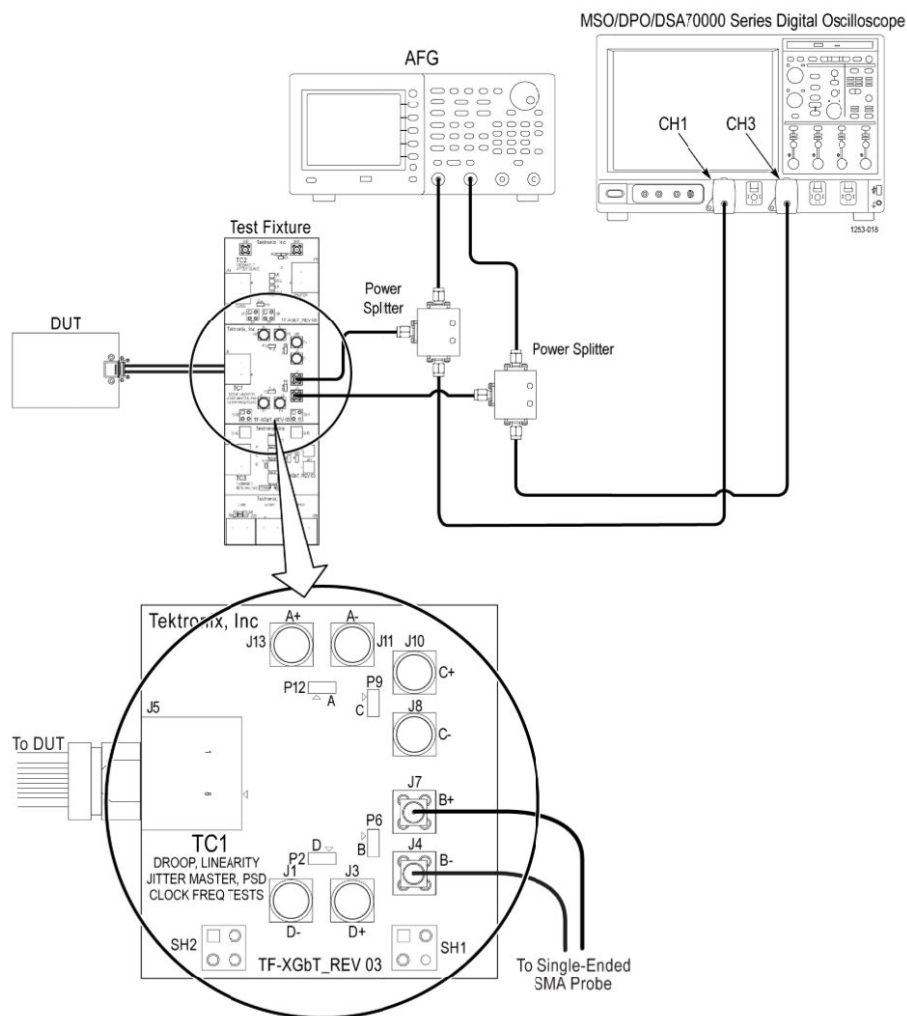


Figure 14: Transmitter non-linear distortion with disturbing signal (Single-Ended)



Note: Total number of splitters used should be equal to twice the number of lanes (D+ and D-) to be tested (used for combining disturbing signal with DUT test mode signal).



Note: Additional splitters are required for testing multilane with AFG or AWG:

- AFG: two splitters for testing every additional lanes.
- AWG: additional splitters depending on the number of lanes to be tested.

Prerequisite

Compensate the signal path

Use the following procedure to compensate the internal signal acquisition path. Perform this procedure if the ambient temperature has changed more than 5 °C (9 °F) since you performed the last signal path compensation. Perform the signal path compensation once a week. Failure to do so may result in the instrument not meeting warranted performance levels.

1. Power on and wait for the instrument to complete its warm up period before continuing with this procedure.

2. Disconnect any probes you have connected to the input channels.
3. Set the instrument to Menu mode.
4. Select Instrument Calibration from the Utilities menu.
5. Note any instructions that appear in the resulting control window.
6. Click Run SPC to begin the procedure. The procedure may take several minutes to complete.
7. Verify that the Status changes to Compensated after the procedure is complete. If the Calibration Status field indicates anything other than Compensated, see Signal Path Compensation Status for information on the readout and recommended action.



Note: When making measurements at vertical scale settings less than or equal to 5 mV, you should perform the signal path compensation at least once a week. Failure to do so may result in the instrument not meeting warranted performance levels at those volts/div settings.

Deskew

If skew is present between positive and negative channels, then the channels need to be deskewed before being used for waveform measurements. provides support for channel deskew using the following method:

1. Determine what the skew is for each channel.
2. From the TekScope menu, select Vertical > Deskew.
3. In the Deskew/Attenuation window, click the channel (1 – 4) button for the first channel to be deskewed.
4. Click in the Ch(x) Deskew Time entry field and enter the skew. The skew can be +ve or –ve.
5. Click the channel button for the next channel and repeat step 4 on page 53.
6. After entering the skew for all the channels that require it, from the Options menu in , select Deskew.
7. In the Deskew dialog box, select the desired level:
 - Less than 100 mV signal amplitude: Select this if the signal amplitude is such that the oscilloscope's vertical setting is less than 100 mV/division.
 - 100 mV or greater signal amplitude: Select this if the signal amplitude is such that the oscilloscope's vertical setting is greater than 100 mV/division.

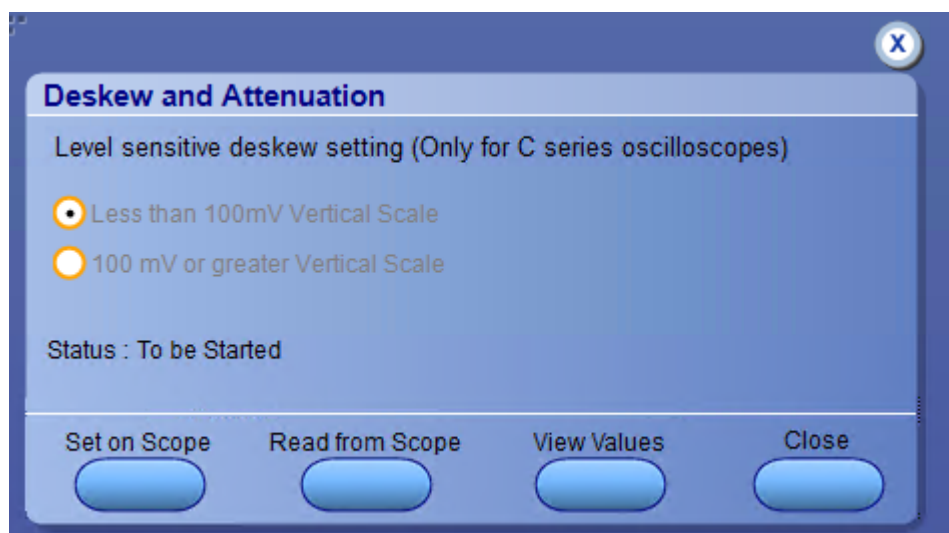


Figure 15: Deskew

8. Click Read Deskew/Attn.
9. When the status in the dialog box indicates the deskew is finished, click Close.

Each input channel has its own deskew settings. Deskew compensates individual channels for probes or cables of different lengths. The instrument applies the delay values after each completed acquisition. The deskew values are saved as part of the instrument setup. The deskew values for the selected channel are retained until you change the probe, you restore a saved setup, or you recall the factory setup.

Signal path compensation for transmitter non-linear distortion with disturbing signals

Use the following procedure to compensate the signal path for transmitter non-linear distortion measurement with disturbing signals:

1. Select **With disturbing signals (45 MHz)** in the Acquire panel of the measurement.
2. Add disturbing signal (Sine wave of 45 MHz) using a Tektronix recommended AWG, AFG, or third party signal generator.
3. Use Combiners to combine the disturbing signal and device test mode signal. If the generator has less outputs, then use splitters in the signal path between generator and combiner.
4. Combiner Effect: Enter the loss occurred values due to combiners. Use the datasheet of the combiners for the values.
5. Compensation Value: Click **Auto Compensate** to automatically calculate the value. You can also manually enter the values in the input field.
6. Enter the Combiner Effect and Compensation Value in such a way that the disturber amplitude is 7 dB less compared to the amplitude linearity tones.



Note: The circuit used to calculate auto compensation only should be used to calculate the measurements.

Running tests

[Select tests](#), [set acquisition parameters](#), [set configuration parameters](#), [set preferences parameters](#), and click **Start** to run the tests. While tests are running, you cannot access the Setup or Reports panels. To monitor the test progress, switch between the Status panel and the Results panel.

While the tests are running, other applications may display windows in the background. The TekScope application takes precedence over other applications, but you can switch to other applications by using **Alt + Tab** key combination. To keep the application on top, select **Keep On Top** from the TekExpress Options menu.

The application displays report when the tests execution is complete.

Prerun checklist

1. Make sure that the instruments are warmed up (approximately 20 minutes) and stabilized.
2. Perform compensation: In the oscilloscope main menu, select **Utilities > Instrument Compensation**. Click **Help** in the compensation window for steps to perform instrument compensation.

Saving and recalling test setup

Test setup files overview

Saved test setup information (such as the selected oscilloscope, general parameters, acquisition parameters, measurement limits, waveforms (if applicable), and other configuration settings) is saved under the setup name at X:\Ethernet Tx.

Use test setups to:

- Run a new session, acquiring live waveforms, using a saved test configuration.
- Create a new test setup based on an existing one.
- View all the information associated with a saved test, including the log file, the history of the test status as it executed, and the results summary.
- Run a saved test using saved waveforms.

See also

[Save a test setup](#)

[Open \(load\) a saved test setup](#)

Save a test setup

You can save a test setup before or after running a test. You can create a test setup from [already opened test setup](#), or using [default test setup](#). When you select the default test setup, the parameters are set to the application's default value.

Select **Options > Save Test Setup** to save the opened setup.

Select **Options > Save Test Setup As** to save the setup with different name.

Open (load) a saved test setup

To Open (load) a saved test setup, do the following:

1. Select **Options > Open Test Setup**.
2. Select the setup from the list and click **Open**. Setup files are located at .

See also

[Create a test setup using an existing one](#)

[Create a test setup from default settings](#)

Create a test setup from default settings

To create a test setup using default settings, follow the steps:

1. Select **Options > Default Test Setup**. For default test setup, the parameters are set to the application's default value.
2. Click application [Setup](#) and set the parameters
3. Click application [Reports](#) and set the report options
4. Optional: Click **Start** to run the test and verify that it runs correctly and captures the specified test information and reports. If it does not, then edit the parameters and repeat this step until the test runs to your satisfaction
5. Select **Options > Save Test Setup**. Enter the file name and click Save. The application saves the file to

Create a test setup using an existing one

To create a test setup using an existing one, follow the steps:

1. Select **Options > Open Test Setup**
2. Select a setup from the list and then click **Open**
3. Click application [Setup](#) and modify the parameters
4. Click application [Reports](#) and modify the report options
5. Select **Options > Save Test Setup As**
6. Enter test setup name, and click **Save**

TekExpress Ethernet Tx measurements

Maximum output droop

This section verifies that the transmitter output level does not drop more than the maximum specified amount.

Required test equipment

[Minimum system requirements](#)

[Supported Probes](#)

[Equipment connection diagram](#)

Inputs

- DUT shall be configured to transmit test mode 6 waveform
- If acquisition is single ended, then provide Data+ and Data- waveforms. If acquisition is differential, then provide differential data waveform as input to the measurement.
- REFLEVEL, MIDLEVEL and HYSTERESIS for edge finding
- START TIME and STOP TIME
- POPULATION
- Number of ACQUISITION AVERAGES

Measurement procedure

1. If acquisition is single ended, then compute differential waveform (scope math) using acquired single ended signals.
2. Compute edges of differential signal using midlevel and hysteresis dialed by the user in the user interface.
3. If Droop type is "POSITIVE" then
 - a. Consider rising edges for further computation. Waveform Edges = rising edges
 Else
 - a. Consider falling edges for further computation. Waveform Edges = falling edges
4. For every edge in Waveform Edges,
 - a. Compute average value of NAVERAGE points around the edge Position + start time. This gives High Voltage.
 - b. Compute average value of NAVERAGE points around the edge Position + stop time. This gives Low Voltage.
 - c. Compute Droop in % = ((High Voltage – Low Voltage)/High Voltage) * 100.
 - d. Store High Voltage, Low Voltage, Edge Position and Droop in %.
5. Compute Maximum, Minimum, Mean and number of Droops from the collected result in step 4 on page 57.
6. Maximum droop in % will be used for comparing with limits given in specification.

Transmitter timing Jitter-Master

This section verifies that the transmitter timing jitter - master of the PMA is within the conformance limits.

Required test equipment

[Minimum system requirements](#)

[Supported Probes](#)

[Equipment connection diagram](#)

Inputs

- DUT shall be configured to transmit test mode 2 waveform
- If acquisition is single ended, then provide Data+ and Data- waveforms. If acquisition is differential then provide differential data waveform as input to measurement.
- REFLEVEL, MIDDLELEVEL and HYSTERESIS for edge finding
- Acquisition duration
- Apply Band Pass Filter – Yes or No

Measurement procedure

1. If Acquisition is SINGLE_ENDED then
 - a. If APPLY FILTER is YES then, APPLY the band pass filter with Fc as (200 MHz/S) with band width as 20 KHz on single ended signals.
 - b. Compute Differential signal (scope math) using acquired single ended signals

Else

 - a. If APPLY FILTER is YES then, APPLY the band pass filter with Fc as (200 MHz/S) with band width as 20 KHz on differential signal.
 - b. Acquire Differential signal
2. Compute edges of differential signal using midlevel and hysteresis dialed by the user in the user interface.
3. Determine the direction of first edge
 - a. If first edge direction is rise, then consider only the rising edges for further computation. Waveform Edges = rising edges
 - b. If first edge direction is fall, then consider only the falling edges for further computation. Waveform Edges = falling edges
4. Do a least square fit using Waveform Edges. X being edge number and Y being edge position.
 Compute slope and intercept. Intercept gives starting edge position. Slope gives ideal duration between Waveform Edges.
 Using Slope and Intercept, reconstruct the ideal position of Waveform Edges.
5. For every Waveform Edge, Compute TIE.

$$TIE = \text{Actual position of Waveform Edges} - \text{Ideal position of Waveform Edges}$$
6. Compute RMS of TIE.
7. RMS of TIE will be used for comparing with limits given in specification

Transmitter timing Jitter-Slave

This section verifies that the transmitter timing jitter slave of the PMA is within the conformance limits.

Required test equipment

[Minimum system requirements](#)

[Supported Probes](#)

[Equipment connection diagram](#)

Inputs

- DUT shall be configured to transmit test mode 6 waveform.
- If acquisition is single ended, then provide Data+ and Data- waveforms. If acquisition is differential then provide differential data waveform as input to measurement.
- REFLEVEL, MIDDLELEVEL and HYSTERESIS for edge finding
- Acquisition duration
- Apply Band Pass Filter – Yes or No

Measurement procedure

1. If Acquisition is SINGLE_ENDED then,
 - a. If APPLY FILTER is YES, then APPLY the band pass filter with Fc as (200 MHz/S) with band width as 20 KHz on single ended signals.
 - b. Compute Differential signal(scope math) using acquired single ended signals
 Else
 - a. If APPLY FILTER is YES then, APPLY the band pass filter with Fc as (200 MHz/S) with band width as 20 KHz on differential signal.
 - b. Acquire Differential signal
2. Compute edges of differential signal using midlevel and hysteresis dialed by the user in the user interface.
3. Determine the direction of first edge.
 - a. If first edge direction is rise, then consider only rising edges for further computation. Waveform Edges = rising edges
 - b. If first edge direction is fall, then consider only falling edges for further computation. Waveform Edges = falling edges
4. Do a least square fit using Waveform Edges. X being edge number and Y being edge position.
 Compute slope and intercept. Intercept gives starting edge position. Slope gives ideal duration between Waveform Edges.
 Using Slope and Intercept, reconstruct the ideal position of Waveform Edges.
5. For every Waveform Edge, Compute TIE.
 TIE = Actual position of Waveform Edges – Ideal position of Waveform Edges.
6. Compute RMS of TIE.
7. RMS of TIE will be used for comparing with limits given in specification

Transmitter Power Spectral Density and Power level

This section verifies that the transmitter Power Spectral Density (PSD) and transmit power level are within the conformance limits.

Required test equipment

[Minimum system requirements](#)

[Supported Probes](#)

[Equipment connection diagram](#)

Inputs

- DUT shall be configured to transmit test mode 6 waveform
- If acquisition is single ended, then provide Data+ and Data- waveforms. If acquisition is differential then provide differential data waveform as input to measurement.
- START FREQUENCY, RESOLUTION BANDWIDTH, STOP FREQUENCY for configuring SPECTRAL MAGNITUDE MATH function
- ACQUISITION AVERAGES
- SMOOTHING AVERAGES – the window size used for smoothing the PSD curve

Measurement procedure

1. If acquisition is single ended, then compute differential waveform (scope math) using acquired single ended signals.
2. Compute the mean of the differential signal, the DC component.
3. Remove the DC component from the differential signal.
 MATH2 = Differential signal – Mean (Differential Signal).
 Mean is computed using scope measurement.
4. Compute the average of spectral magnitude of MATH2

MATH3 = AVG (SpectralMag (MATH2))

SpectralMag settings are as follows:

- Center Frequency: STOP FREQUENCY/2
- Frequency Span: STOP FREQUENCY
- Window Type: GAUSSIAN
- Vertical Axis Scale: Linear
- MATH3 averages: ACQUISITION AVERAGES
- Resolution Bandwidth: RESOLUTION BANDWIDTH
 - Gate position = 0
 - Gate Duration = (2/Resolution Bandwidth in Hz)

Factor of 2 is because of Gaussian window

- Do a moving average of spectral signal with number of averages equal to SMOOTHING AVERAGES dialed by user in user interface.
- Compute linear power spectrum of moving averaged signal. Determine the area under the linear power spectrum.
- Compute the offset/correction value.

Offset/correction value = function (Resolution Bandwidth configured by user, termination resistance of 100 Ohm, dB to dBm conversion factor, constant factor of 1.05)

Offset/correction value = $10 \cdot \log_{10}(\text{dB to dBm conversion factor}) - 10 \cdot \log_{10}(\text{Resolution Bandwidth}) - 10 \cdot \log_{10}(\text{termination resistance}) + \text{constant factor}$

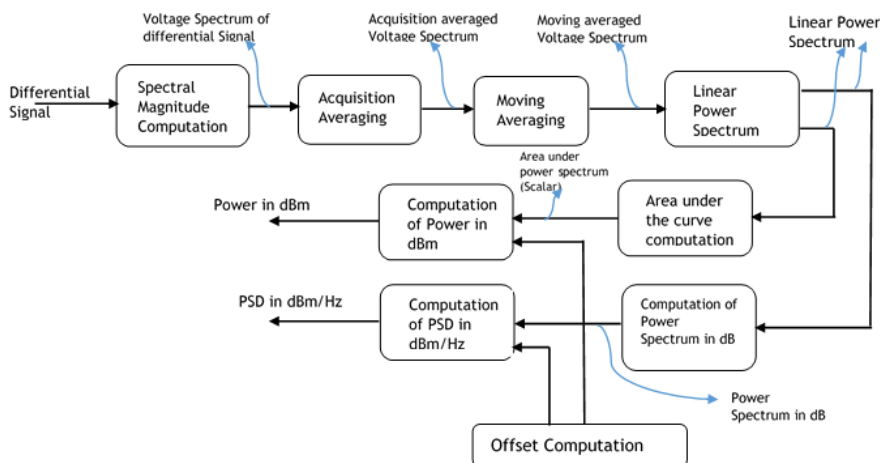
Offset/correction value = $10 \cdot \log_{10}(1000) - 10 \cdot \log_{10}(\text{Resolution Bandwidth}) - 10 \cdot \log_{10}(100) + 1.05$

Offset/correction value = $11.05 - 10 \cdot \log_{10}(\text{Resolution Bandwidth})$

- Power in dBm = $10 \cdot \log_{10}(\text{Area under the linear power spectrum}) + \text{Offset value}$
- Convert power spectrum in linear scale to dB scale.
- Compute power spectrum in dBm/Hz

Power Spectrum in dBm/Hz = power spectrum in dB + Offset value

- Power in dBm is compared with limits given in specification
- PSD curve is compared with limit curve given in specification



Transmitter clock frequency

This section verifies that the frequency of the transmit clock is within the conformance limits.

Required test equipment[Minimum system requirements](#)[Supported Probes](#)[Equipment connection diagram](#)**Inputs**

- DUT shall be configured to transmit test mode 6 waveform
- If acquisition is single ended, then provide Data+ and Data- waveforms. If acquisition is differential then provide differential data waveform as input to measurement.
- REFLEVEL, MIDDLELEVEL and HYSTERESIS for edge finding.

Measurement procedure

1. If acquisition is single ended, then compute differential waveform (scope math) using acquired single ended signals.
2. Compute edges of differential signal using midlevel and hysteresis dialed by the user in the user interface.
3. Compute edge to edge duration
4. Determine the mean, maximum and minimum edge to edge duration
5. Determine the mean deviation, maximum deviation and minimum deviation in terms of ppm from the nominal frequency (edge to edge frequency of test mode 2 signal).

Mean deviation in terms of ppm = $((1/\text{mean edge to edge duration}) - \text{Expected edge to edge period}) * 1e6 / \text{Expected edge to edge period}$

Maximum deviation in terms of ppm = $((1/\text{minimum edge to edge duration}) - \text{Expected edge to edge period}) * 1e6 / \text{Expected edge to edge period}$

Minimum deviation in terms of ppm = $((1/\text{maximum edge to edge duration}) - \text{Expected edge to edge period}) * 1e6 / \text{Expected edge to edge period}$

6. Mean deviation in ppm is compared with limits.

Transmitter non-linear distortion

This section verifies that the output of the transmitter conforms to the transmitter linearity requirements.

Required test equipment[Minimum system requirements](#)[Supported Probes](#)[Equipment connection diagram](#)**Inputs**

- DUT shall be configured to transmit test mode 6 waveform
- If acquisition is single ended, then provide Data+ and Data- waveforms. If acquisition is differential then provide differential data waveform as input to measurement.
- START FREQUENCY, RESOLUTION BANDWIDTH, STOP FREQUENCY for configuring SPECTRAL MAGNITUDE MATH function
- ACQUISITION AVERAGES

Measurement procedure (10GBase-T, 5GBase-T, and 2.5GBase-T)

1. If acquisition is single ended, then compute differential waveform (scope math) using acquired single ended signals.
2. Compute the average of spectral magnitude of differential signal

MATH3 = AVG (SpectralMag (Differential Signal))

SpectralMag settings are as follows:

- Center Frequency: STOP FREQUENCY/2
- Frequency Span: STOP FREQUENCY
- Window Type: GAUSSIAN
- Vertical Axis Scale: dB
- MATH3 averages: ACQUISITION AVERAGES
- Resolution Bandwidth: RESOLUTION BANDWIDTH
- Gate position = 0
- Gate Duration = (2/Resolution Bandwidth in Hz)

Factor of 2 is because of Gaussian window

3. Determine the peaks (two) and their corresponding frequencies in the spectrum.
4. Check whether peaks correspond to the tone pair (based on the sub-test selected). If not then exit the test.
5. Intermodulation frequencies for above found peak frequencies and their corresponding amplitudes up to 20th order are found using the spectrum
6. Determine the intermodulation distortion.

Intermodulation distortion = Sum (Amplitudes of IMF for above found peak frequencies up to 5th order) / Sum (Amplitudes of peak frequencies)

Intermodulation distortion in % = Intermodulation distortion * 100

7. Spurious Frequency Dynamic Range (SFDR) = Minimum (Amplitudes of peak frequencies) – Maximum (Amplitudes of IMF).
8. SFDR is compared with limits given in specification.

Transmitter non-linear distortion (with disturbing signals)

This section verifies that the output of the transmitter conforms to the transmitter linearity requirements.

Required test equipment

[Minimum system requirements](#)

[Supported Probes](#)

[Equipment connection diagram](#)

Inputs

- DUT shall be configured to transmit test mode 6 waveform
- If acquisition is single ended, then provide Data+ and Data- waveforms. If acquisition is differential then provide differential data waveform as input to measurement.
- START FREQUENCY, RESOLUTION BANDWIDTH, STOP FREQUENCY for configuring SPECTRAL MAGNITUDE MATH function
- ACQUISITION AVERAGES

Prerequisite

[Compensate signal path for transmitter non-linear distortion with disturbing signals](#)



Note: The circuit used to calculate auto compensation only should be used to calculate the measurements.

Measurement procedure (2.5GBase-T - with disturbing signals)

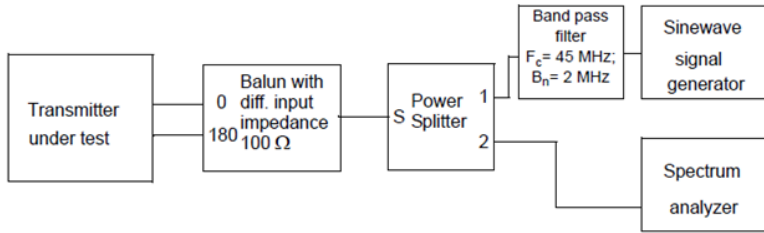


Figure 16: Transmitter Test fixture 4 for linearity measurement of 2.5GBaseT with Sine wave injection

1. If acquisition is single ended, then compute differential waveform (scope math) using acquired single ended signals.
2. For each pair of transmitter fixtures, inject 45 MHz signal having amplitude of 7 db below the peak of the transmitter at the MDI.
3. Feed the 45 MHz signal along with differential input signal as separate inputs to a Power splitter and take the mixed signal as output.
4. Compute the average of spectral magnitude of differential signal

MATH3 = AVG (SpectralMag (Differential Signal))

SpectralMag settings are as follows:

- Center Frequency: STOP FREQUENCY/2
- Frequency Span: STOP FREQUENCY
- Window Type: GAUSSIAN
- Vertical Axis Scale: dB
- MATH3 averages: ACQUISITION AVERAGES
- Resolution Bandwidth: RESOLUTION BANDWIDTH
- Gate position = 0
- Gate Duration = (2/Resolution Bandwidth in Hz)

Factor of 2 is because of Gaussian window

- Determine the peaks (two) and their corresponding frequencies in the spectrum.
5. Determine the peaks (two) and their corresponding frequencies in the spectrum.
 6. Check whether peaks correspond to the tone pair (based on the sub-test selected). If not then exit the test.
 7. Intermodulation frequencies for above found peak frequencies and their corresponding amplitudes up to 20th order are found using the spectrum
 8. Determine the intermodulation distortion.

Intermodulation distortion = Sum (Amplitudes of IMF for above found peak frequencies up to 5th order) / Sum (Amplitudes of peak frequencies)

Intermodulation distortion in % = Intermodulation distortion * 100

9. Spurious Frequency Dynamic Range (SFDR) = Minimum (Amplitudes of peak frequencies) – Maximum (Amplitudes of IMF).
10. SFDR is compared with limits given in specification.

MDI return loss

This section verifies that the return loss of the DUT is within conformable limits.

Required test equipment

[Minimum system requirements](#)

[Supported Probes](#)

Equipment connection diagram

Return loss is a measure of the signal power that is reflected due to the impedance mismatch.

$$\text{Return loss} = 20 \cdot \log_{10} (\text{Reflected} / \text{Incident})$$

Return loss describes the degree of mismatch between a load and characteristic impedance of a transmission system.

Return loss measurement setup involves fixture, AWG, AWG signal, probes, DUT and oscilloscope. Return loss measurement can be divided into 3 steps

- Return Loss calibration
- Computation of error coefficients
- Computation of return loss

1. Return Loss Calibration

Inputs

- Wide band calibration signal transmitted from AWG.
- Let RJ45 patch chord be connected to open impedance.
- Waveform acquired using a probe connected to input of reference impedance – waveform1
- Waveform acquired using a probe connected to input of DUT cable under test – waveform2
- ACQUISITION AVERAGES → Used for averaging acquired time domain signal
- SMOOTHING AVERAGES → Used internally by C# module for smoothing the return loss curve

Calibration procedure

- Incident Signal = Waveform2 + (Waveform1 – Waveform2) = Waveform1
- Reflected Signal = Waveform2 – (Waveform1 – Waveform2) = 2*Waveform2 – Waveform1
- Compute FFT of incident signal and FFT reflected signal
 - Real Part of FFT of Incident Signal = (SpectralReal (Waveform1))
 - Imaginary Part of FFT of Incident Signal = (Spectrallmag (Waveform1))
 - Real Part of FFT of Reflected Signal = (SpectralReal (2*Waveform2 – Waveform1))
 - Imaginary Part of FFT of Reflected Signal = (Spectrallmag (2*Waveform2 – Waveform1))
- Compute Gamma (return loss without error correction) as complex division of reflected signal by incident signal
 - Gamma = Complex (Real Part of FFT of Reflected Signal, Imaginary Part of FFT of Reflected Signal) / Complex (Real Part of FFT of Incident Signal, Imaginary Part of FFT of Incident Signal)
- Repeat steps 1.a on page 64 to 1.d on page 64 with waveform1 and waveform2 captured using short and load impedance (100 Ohm).

2. Computation of Error Coefficients

Inputs

- Gamma (Complex) values computed with different loads – open, short and load (Γ_{m1} , Γ_{m2} , Γ_{m3})

Procedure/Steps:

- Compute error coefficients a, b and c using Γ_{m1} , Γ_{m2} and Γ_{m3} values

$$a = \Gamma_{m2} - \Gamma_{m3} + \frac{\Gamma_{m1} - \Gamma_{m2}}{\Gamma_{m2} + \Gamma_{m1}} \cdot \Gamma_{m2}$$

$$b = \Gamma_{m3}$$

$$c = \frac{\Gamma_{m1} - \Gamma_{m2}}{\Gamma_{m2} + \Gamma_{m1}}$$

3. Computation of Return Loss

Inputs

- Wide band calibration signal transmitted from AWG.
- Let RJ45 patch chord be connected to DUT.
- Waveform acquired using a probe connected to input of reference impedance – waveform1
- Waveform acquired using a probe connected to input of DUT cable under test – waveform2
- Error coefficients a, b and c
- ACQUISITION AVERAGES → Used for averaging acquired time domain signal
- SMOOTHING AVERAGES → Used internally by C# module for smoothing the return loss curve

Procedure/Steps:

- Incident Signal = Waveform2 + (Waveform1 – Waveform2) = Waveform1
- Reflected Signal = Waveform2 – (Waveform1 – Waveform2) = 2*Waveform2 – Waveform1
- Compute FFT of incident signal and FFT reflected signal
 Real Part of FFT of Incident Signal = (SpectralReal (Waveform1))
 Imaginary Part of FFT of Incident Signal = (Spectrallmag (Waveform1))
 Real Part of FFT of Reflected Signal = (SpectralReal (2*Waveform2 – Waveform1))
 Imaginary Part of FFT of Reflected Signal = (Spectrallmag (2*Waveform2 – Waveform1))
- Compute Gamma (return loss/reflection coefficient without error correction) as complex division of reflected signal by incident signal (Γ_m)
 Gamma = Complex (Real Part of FFT of Reflected Signal, Imaginary Part of FFT of Reflected Signal) / Complex (Real Part of FFT of Incident Signal, Imaginary Part of FFT of Incident Signal)
- Compute error corrected reflection coefficient

$$\Gamma_A = \frac{\Gamma_m - b}{a - c\Gamma_m}$$

- Compute return loss in dB scale as Return Loss = 20*log10 (Absolute (Γ_A))
- Re-normalize the return loss to 85 Ohm and 115 Ohm.

$$\text{Gamma at } Z1 \text{ Ohm} = \frac{\beta + \Gamma A}{1 + \beta \cdot \Gamma A}$$

$$\text{where } \beta = \frac{Z_A - Z_1}{Z_A + Z_1}$$

$Z_A \rightarrow 100 \text{ Ohm}$

$Z_1 \rightarrow 85 \text{ Ohm or } 115 \text{ Ohm}$

$\Gamma A \rightarrow$ Reflection coefficient with 100 Ohm impedance

Return Loss at $Z_1 \text{ Ohm} = 20 \cdot \log_{10} (\text{Absolute (Gamma at } Z_1 \text{ Ohm)})$

h. Return Loss curve is compared with limits given in specification.

SCPI commands

About SCPI command

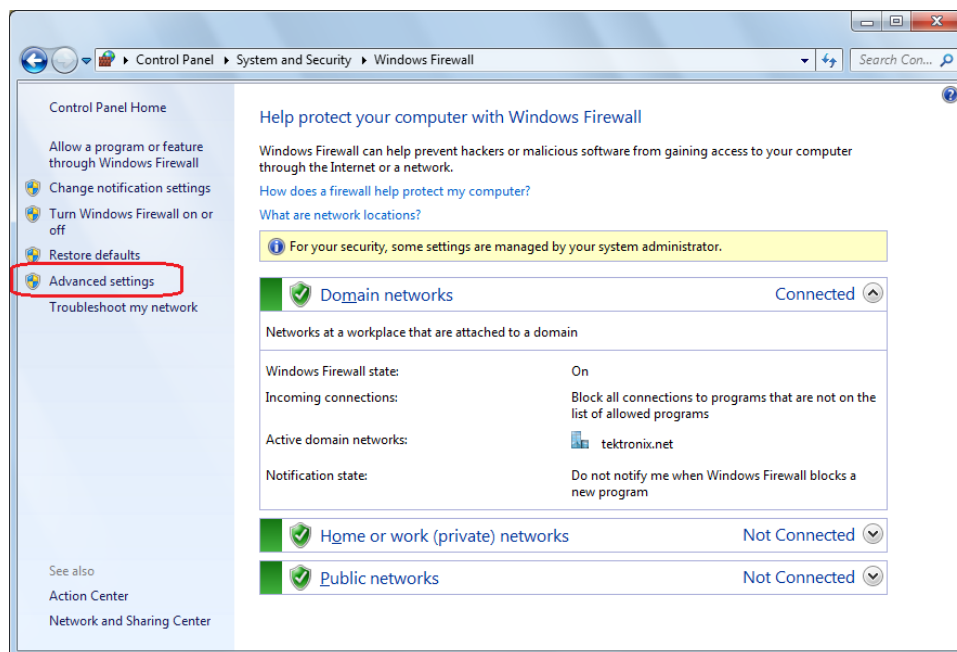
You can use Standard Commands for Programmable Instruments (SCPI) to communicate with the TekExpress application.

Socket configuration for SCPI commands

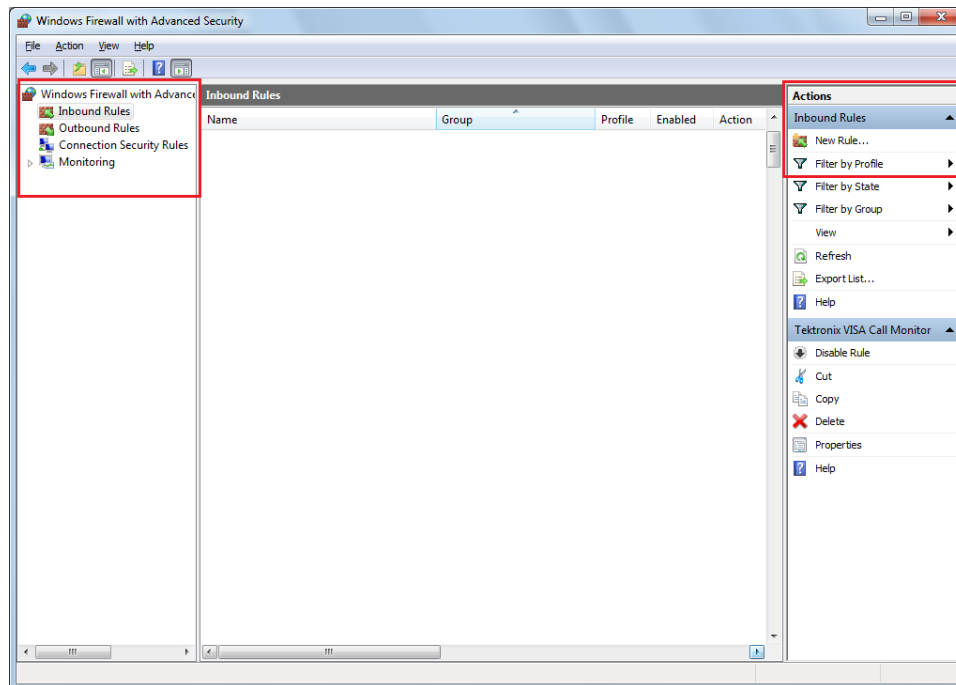
This section describes the steps for TCP/IP socket configuration and TekVISA configuration to execute the SCPI commands.

TCP/IP socket configuration

1. Click **Start > Control Panel > System and Security > Windows Firewall > Advanced settings**.

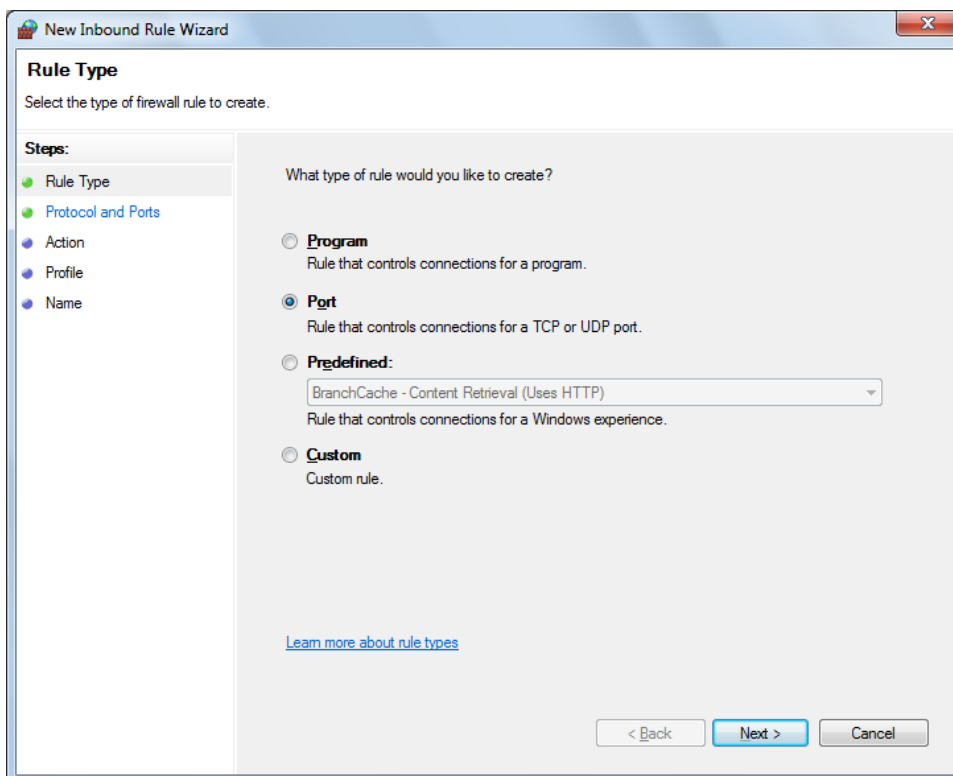


2. In Windows Firewall with Advanced Security menu, select **Windows Firewall with Advanced Security on Local Computer > Inbound Rules** and click New Rule...

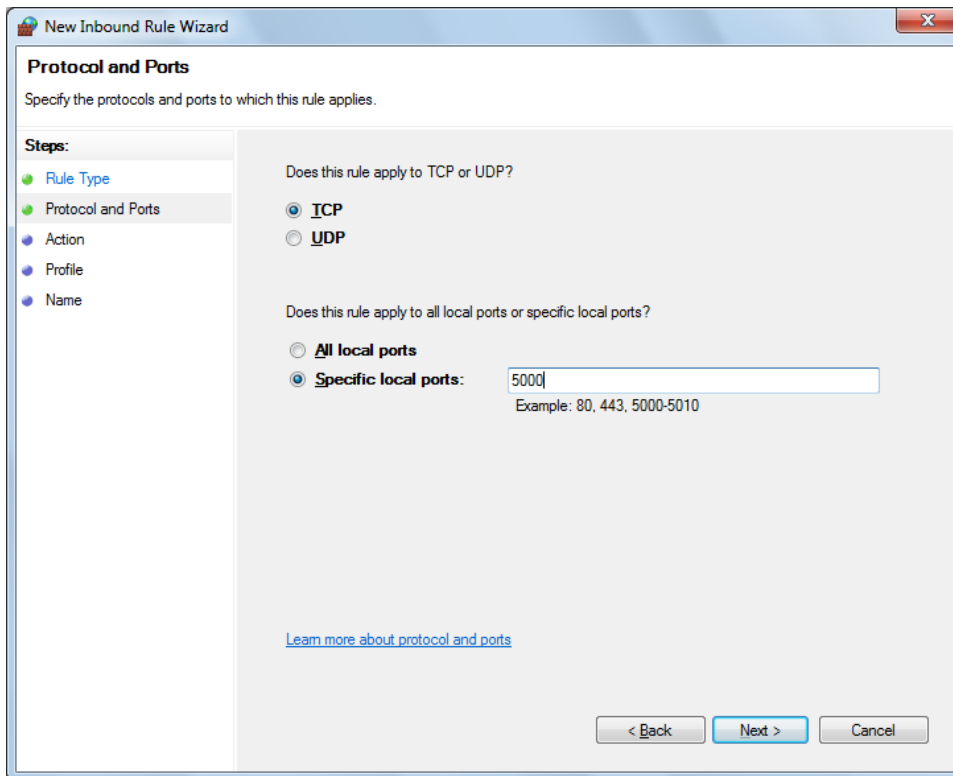


3. In New Inbound Rule Wizard menu

a. Select **Port** and click **Next**.



b. Select **TCP** as rule apply and enter 5000 for **Specific local ports** and click **Next**.



The screenshot shows the 'New Inbound Rule Wizard' window, specifically the 'Protocol and Ports' step. The left sidebar lists the steps: Rule Type, Protocol and Ports (selected), Action, Profile, and Name. The main area contains the following text and options:

Specify the protocols and ports to which this rule applies.

Does this rule apply to TCP or UDP?

☒ TCP
☐ UDP

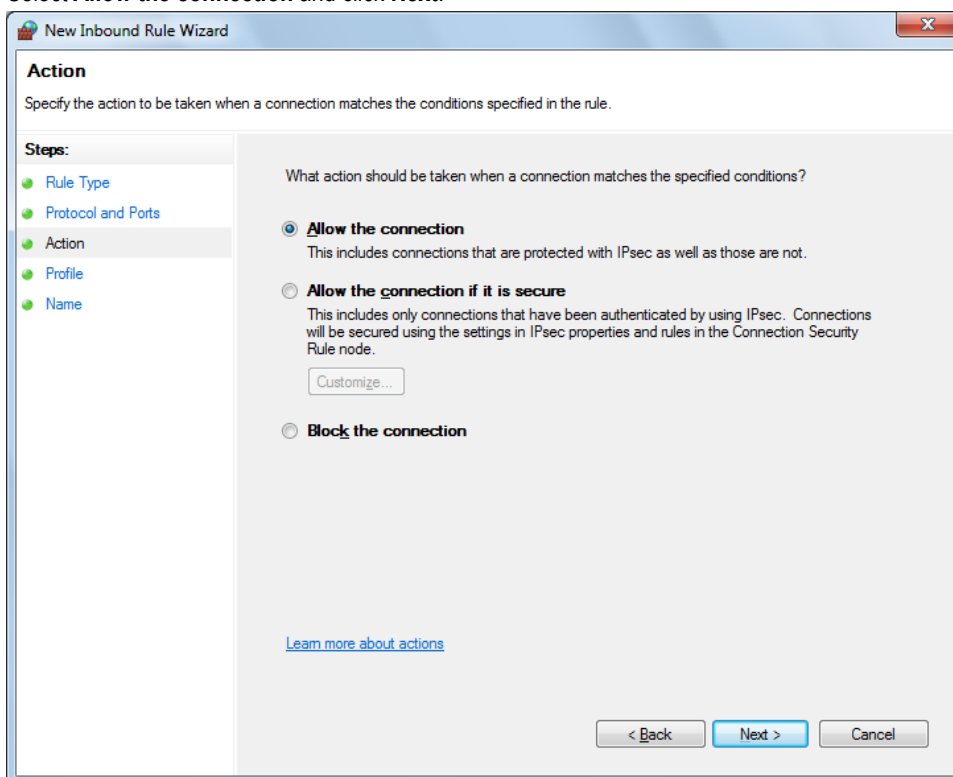
Does this rule apply to all local ports or specific local ports?

☐ All local ports
☒ Specific local ports:
Example: 80, 443, 5000-5010

[Learn more about protocol and ports](#)

At the bottom are buttons for '< Back', 'Next >', and 'Cancel'.

- c. Select **Allow the connection** and click **Next**.



The screenshot shows the 'New Inbound Rule Wizard' window, specifically the 'Action' step. The left sidebar lists the steps: Rule Type, Protocol and Ports, Action (selected), Profile, and Name. The main area contains the following text and options:

Specify the action to be taken when a connection matches the conditions specified in the rule.

What action should be taken when a connection matches the specified conditions?

☒ **Allow the connection**
This includes connections that are protected with IPsec as well as those are not.

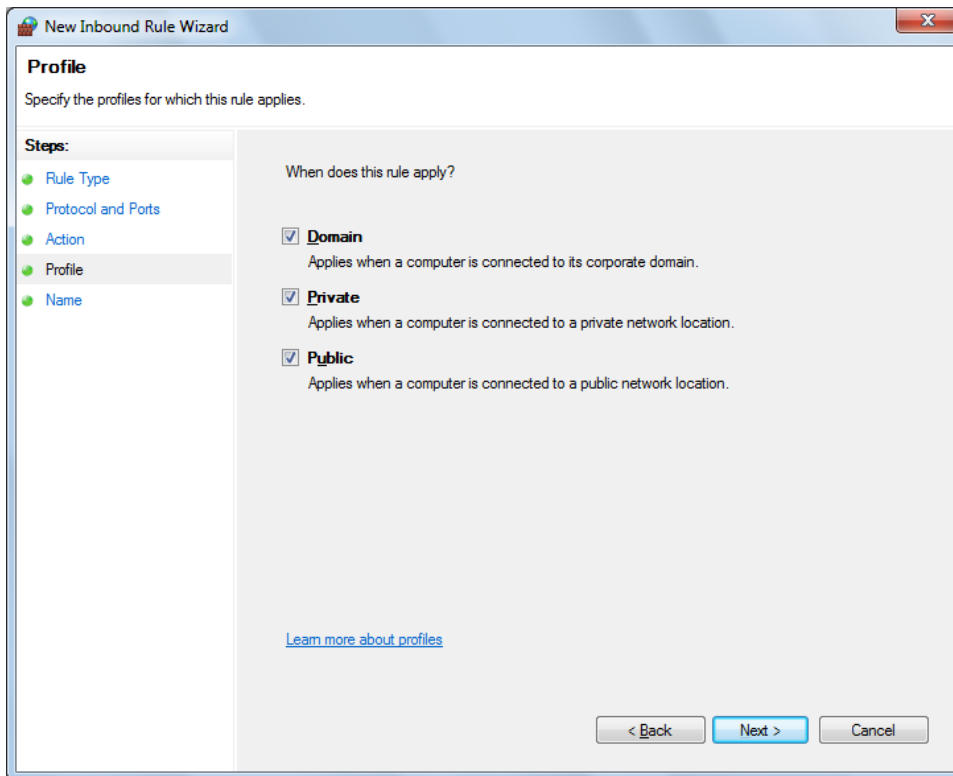
☐ **Allow the connection if it is secure**
This includes only connections that have been authenticated by using IPsec. Connections will be secured using the settings in IPsec properties and rules in the Connection Security Rule node.

☐ **Block the connection**

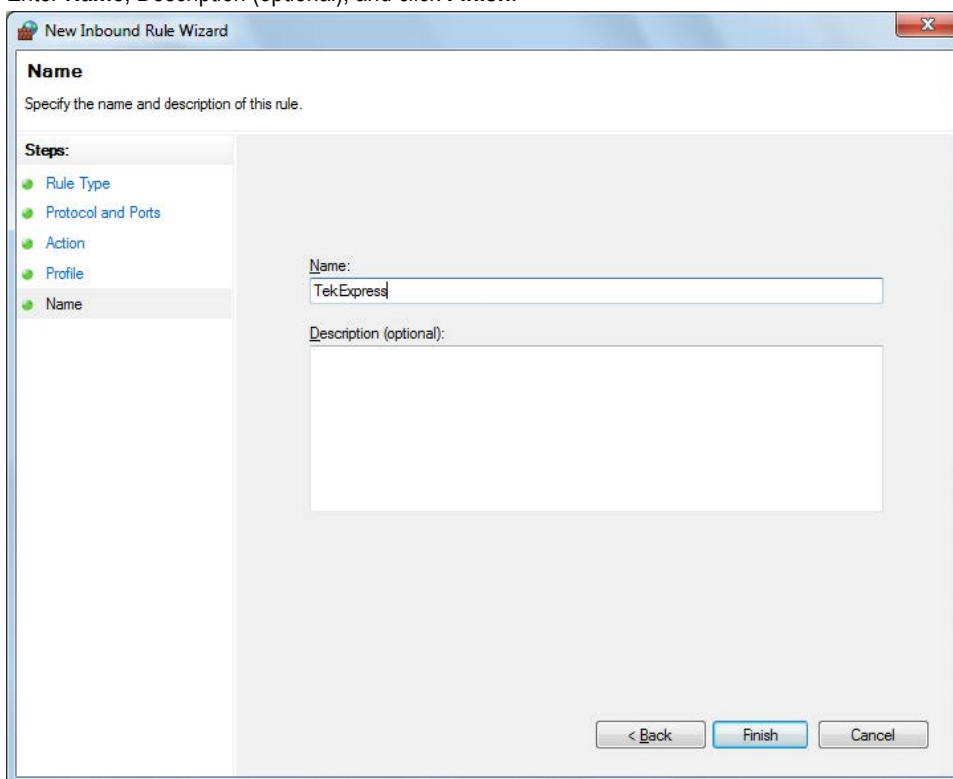
[Learn more about actions](#)

At the bottom are buttons for '< Back', 'Next >', and 'Cancel'.

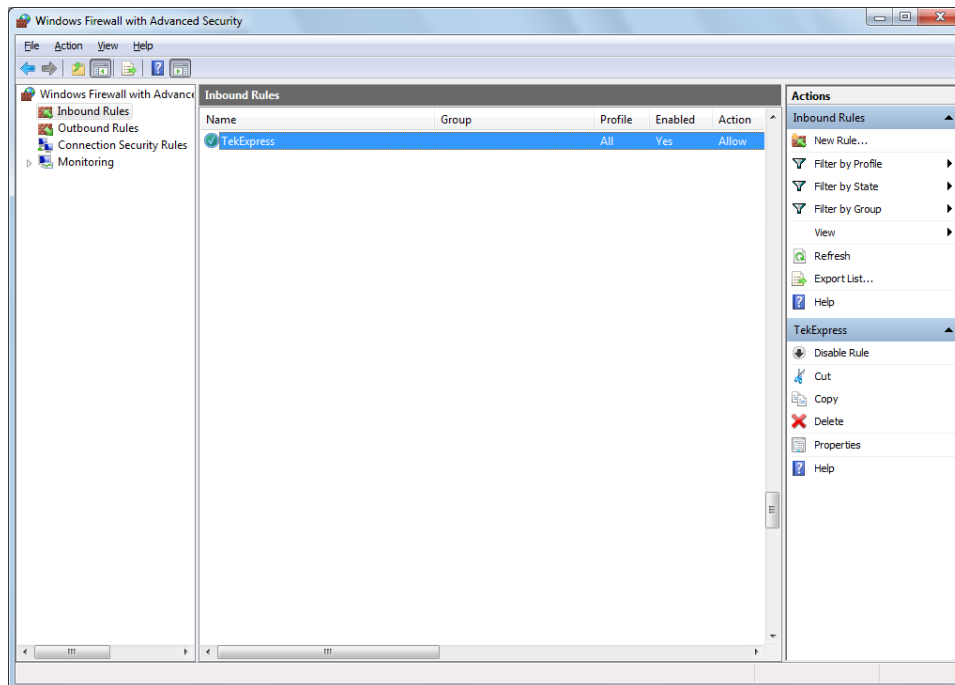
- d. Select **Domain, Private, Public** and click **Next**.



- e. Enter **Name**, **Description** (optional), and click **Finish**.

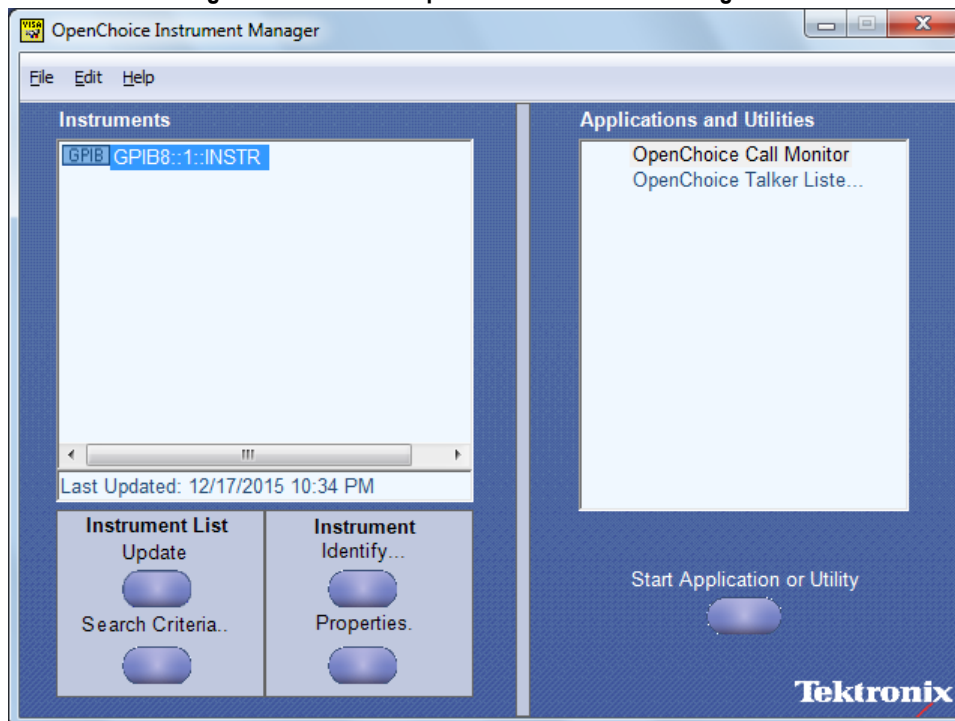



4. Check whether the Rule name is displayed in **Windows Firewall with Advanced Security** menu > **Inbound Rules**.



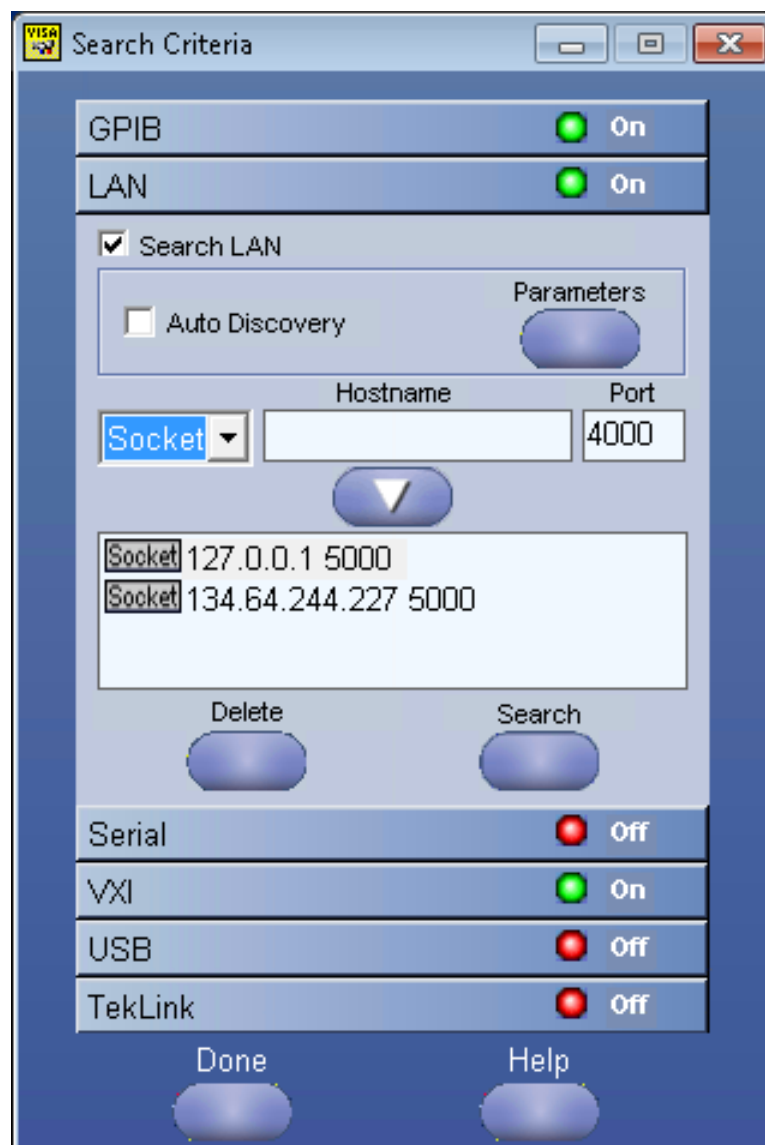
TekVISA configuration

1. Click **Start > All Programs > TekVISA > OpenChoice Instrument Manager**.

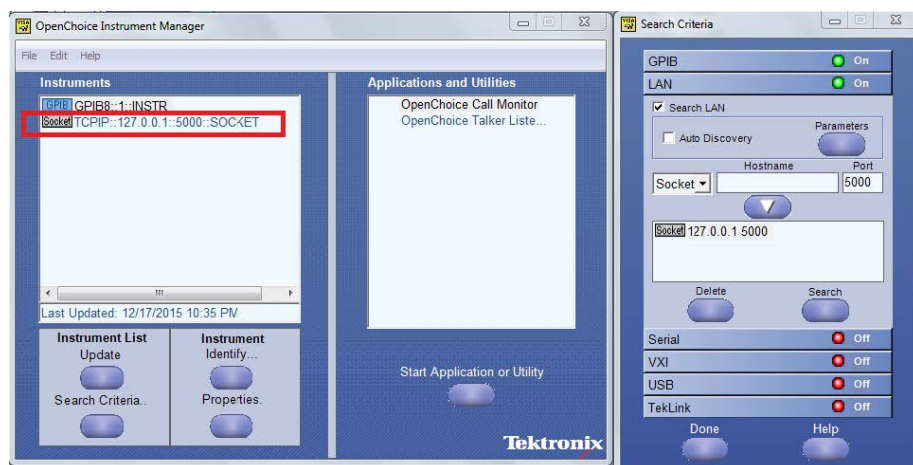


2. Click **Search Criteria**. In Search Criteria menu, click **LAN** to Turn-on. Select **Socket** from the drop-down list, enter the IP address of the TekExpress device in **Hostname** and type **Port** as 5000. Click  to configure the IP address with Port.

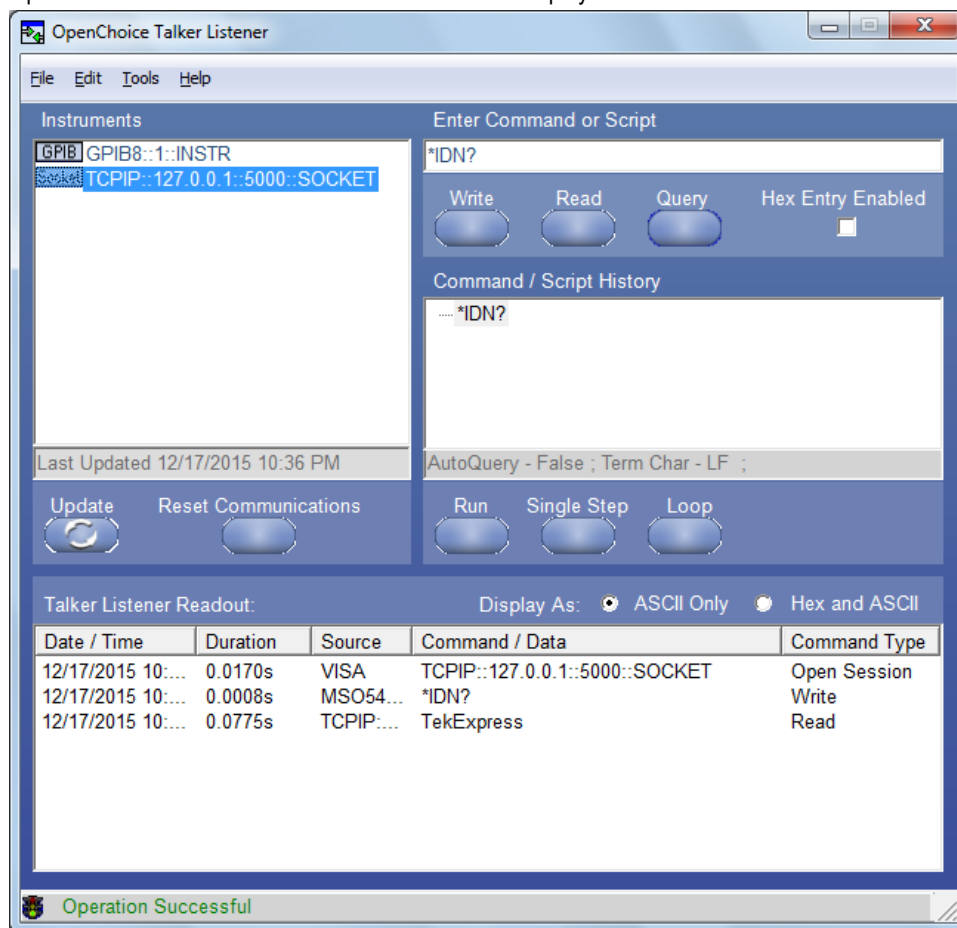
Enter the Hostname as 127.0.0.1 if the TekVISA and TekExpress application are in the same system, else enter the IP address of the TekExpress application system.



3. Click **Search** to setup the TCPIP connection with the host. Check whether the TCPIP host name is displayed in **OpenChoice Instrument Manager > Instruments**.



4. Double-click **OpenChoice Talker Listener** and enter the Command ***IDN?** in command entry field and click **Query**. Check that the Operation is successful and Talker Listener Readout displays the Command / Data.



TEKEXP:*IDN?

This command queries the active TekExpress application name running on the oscilloscope.

Syntax

TEKEXP: *IDN? \n

Inputs

NA

Outputs

Returns active TekExpress application name running on the oscilloscope.

TEKEXP:*OPC?

This command queries the execution status of the last executed command.

Syntax

```
TEKEXP:*OPC?\n
```

Inputs

NA

Outputs

0 - last command execution is not complete

1 - last command execution is complete

TEKEXP:ACQUIRE_MODE

This command sets the acquire mode as live or pre-recorded.

Syntax

```
TEKEXP:ACQUIRE_MODE {LIVE | PRE-RECORDED}\n
```

Inputs

```
{LIVE | PRE-RECORDED}
```

Outputs

NA

TEKEXP:ACQUIRE_MODE?

This command queries the acquire mode type.

Syntax

```
TEKEXP:ACQUIRE_MODE?\n
```

Inputs

NA

Outputs

```
{LIVE | PRE-RECORDED}
```

TEKEXP:EXPORT

This command returns all the bytes of data to the specified file.

Syntax	Outputs
TEKEXP:EXPORT REPORT\n	Returns the report file in bytes
TEKEXP:EXPORT WFM, "<FileName>"\n	Returns the specified waveform file in bytes
TEKEXP:EXPORT IMAGE, "<FileName>"\n	Returns the specified image file in bytes

Inputs

FileName - Specifies the file name

TEKEXP:INFO?

This command queries the information about the file(s).

Syntax	Outputs
TEKEXP:INFO? REPORT\n	<ReportFileSize>,"<ReportFileName.mht>"
TEKEXP:INFO? WFM\n	<WfmFile1Size>,"<WfmFileName1.wfm>";<WfmFile2Size>,"<WfmFileName2.wfm>";...
TEKEXP:INFO? IMAGE\n	<Image1FileSize>,"<Image1FileName>";<Image2FileSize>,"<Image2FileName>" ;...

TEKEXP:INSTRUMENT

This command sets the value for the selected instrument type.

Syntax

TEKEXP:INSTRUMENT "<InstrumentType>",<Value>"\n

Inputs

InstrumentType

Value



Tip: Check *Command parameters list* section for InstrumentType and Value parameters.

Outputs

NA

TEKEXP:INSTRUMENT?

This command queries the instrument selected for the specified instrument type.

Syntax

TEKEXP:INSTRUMENT? "<InstrumentType>"\n

Inputs

InstrumentType



Tip: Check *Command parameters list* section for InstrumentType parameters.

Outputs

Returns the instrument selected for the specified instrument type

TEKEXP:LASTERROR?

This command queries the last error string occurred for the current TCP session. If there are no errors since startup, or since the last call to TEKEXP:LASTERROR?, this command returns an empty string.

Syntax

TEKEXP:LASTERROR?\n

Inputs

NA


Outputs

<string>

TEKEXP:LIST?

This command queries the list of available device, suite, test, version or instrument.

Syntax	Outputs
TEKEXP:LIST? DEVICE\n	Returns the list of available device(s) as comma separated values.
TEKEXP:LIST? SUITE\n	Returns the list of available suite(s) as comma separated values.
TEKEXP:LIST? TEST\n	Returns the list of available test(s) as comma separated values.
TEKEXP:LIST? VERSION\n	Returns the list of available version(s) as comma separated values.
TEKEXP:LIST? INSTRUMENT, "<InstrumentType>"\n	Returns the list of available instruments' for the given Instrument type as comma separated values.

 **Note:** This command returns the list of items within double quotes (""). Iterate the receive procedure until the list ends with double quotes otherwise the next query commands won't work as expected.

Inputs

InstrumentType

 **Tip:** Check *Command parameters list* section for Instrument Type parameters.

TEKEXP:MODE

This command sets the execution mode as compliance or user defined.

Syntax

TEKEXP:MODE {COMPLIANCE | USER-DEFINED}\n

Inputs

{COMPLIANCE | USER-DEFINED}

Outputs

NA

TEKEXP:MODE?

This command queries the execution mode type.

Syntax

```
TEKEXP:MODE?\n
```

Inputs

NA

Outputs

{COMPLIANCE | USER-DEFINED}

TEKEXP:POPUP

This command sets the response to the active popup shown in the application.

Syntax

```
TEKEXP:POPUP "<PopupResponse>"\n
```

Inputs

PopupResponse

Outputs

NA

TEKEXP:POPUP?

This command queries the active popup information shown in the application.

Syntax

```
TEKEXP:POPUP?\n
```

Inputs

NA

Outputs

Returns the active popup information in the application.

TEKEXP:REPORT

This command generates the report for the current session.

Syntax

```
TEKEXP:REPORT GENERATE\n
```

Inputs

GENERATE

Outputs

NA

TEKEXP:REPORT?


This command queries the queried header field value in the report.

Syntax

TEKEXP:REPORT? "<HeaderField>"\n

Inputs

HeaderField - Specifies to return the measured value for the indicated test.

 **Tip:** Check **Report** for HeaderField parameters.

Outputs

Returns the queried header field value in the report

TEKEXP:RESULT?

This command queries the result available in report summary/details table.


Syntax	Outputs
TEKEXP:RESULT? "<TestName>"\n	Return Pass/Fail status of the test.
TEKEXP:RESULT? "<TestName>", "<ColumnName>"\n	Returns all the row values of the specified column for the test.
TEKEXP:RESULT? "<TestName>", "<ColumnName>", <RowNumber>\n	Returns the column value for the specified row number ⁵

Inputs

TestName - Specifies the name of the test for which to obtain the test result value.

ColumnName - Specifies the column name for the measurement

RowNumber - Specifies the row number of the measurement

 **Tip:** Check **Results** panel for TestName, ColumnName, and RowNumber parameters.

TEKEXP:SELECT

This command selects the device, suite, version, or test.

⁵ Row number starts from zero.

Syntax

```
TEKEXP:SELECT <string1>,<string2>,<string4>\n
TEKEXP:SELECT TEST,<string3>,<string4>\n
```

Inputs

```
<string1> = {DEVICE | SUITE | VERSION}
<string2> = {DeviceName | SuiteName | VersionName}
<string3> = {"<TestName>" | ALL | REQUIRED }
<string4> = {TRUE | FALSE}
```



Tip: Check *Command parameters list* section for DeviceName, SuiteName, VersionName, and TestName parameters.

Outputs

NA

TEKEXP:SELECT?

This command queries the name of the selected device, suite, version, or test.

Syntax

```
TEKEXP:SELECT? {DEVICE | SUITE | TEST | VERSION}\n
```

Inputs

```
{DEVICE | SUITE | TEST | VERSION}
```

Outputs

Returns the name of the selected device, suite, version, or test.

TEKEXP:SETUP

This command sets the value of the current setup.

Syntax	Outputs
TEKEXP:SETUP DEFAULT\n	Restore to default Setup
TEKEXP:SETUP OPEN,"<SessionName>"\n	Open the session
TEKEXP:SETUP SAVE\n	Saves the already existing modified session
TEKEXP:SETUP SAVE,"<SessionName>"\n	Save the session

Inputs

SessionName - The name of the session

TEKEXP:STATE

This command sets the execution state of the application.

Syntax

TEKEXP:STATE {RUN | STOP | PAUSE | RESUME}\n

Inputs

{RUN | STOP | PAUSE | RESUME}

Outputs

NA

TEKEXP:STATE?

This command queries the current setup state.

Syntax	Outputs
TEKEXP:STATE?	RUNNING PAUSED WAIT ERROR READY
TEKEXP:STATE? SETUP	SAVED NOT_SAVED

TEKEXP:VALUE


This command sets the value of parameters of type General, Acquire, Analyze, or DUTID.

Syntax

TEKEXP:VALUE GENERAL,"<ParameterName>","<Value>"\n
TEKEXP:VALUE ACQUIRE,"<TestName>","<AcquireType>","<ParameterName>","<Value>"\n
TEKEXP:VALUE ANALYZE,"<TestName>","<ParameterName>". "<Value>"\n
TEKEXP:VALUE DUTID,"<Value>"\n
TEKEXP:VALUE VERBOSE,{TRUE | FALSE}\n
TEKEXP:VALUE WFMFILE,<Test_Name>,<Aquire_Type>,<FileName1\$FileName2>\n

Inputs

- ParameterName - Specifies the parameter name
- TestName - Specifies the test name
- AcquireType - Specifies the acquire type
- Value - Specifes the value to set
- FileName1\$FileName2 - Specifies the waveform file name
- TRUE - Pop-ups are enabled
- FALSE - Pop-ups are disabled

 **Tip:** Check *Command parameters list* section for ParameterName, AcquireType, and Value parameters.

Outputs

NA

TEKEXP:VALUE?

This command queries the value of the parameter for type General, Acquire, Analyze, or DUTID.

Syntax	Outputs
TEKEXP:VALUE? GENERAL, "<ParameterName>"\n	Returns the value of Parameter for type GENERAL
TEKEXP:VALUE? ACQUIRE, "<TestName>", "<AcquireType>", "<ParameterName>"\n	Returns the value of Parameter for type ACQUIRE
TEKEXP:VALUE? ANALYZE, "<TestName>", "<ParameterName>"\n	Returns the value of Parameter for type ANALYZE
TEKEXP:VALUE? DUTID\n	Returns the DUTID value
TEKEXP:VALUE? WFMFILE, <Test_Name>, <Aquire_Type>\n	Returns the waveform file name
TEKEXP:VALUE? VERBOSE	Returns the verbose mode type

Inputs

ParameterName - Specifies the parameter name

TestName - Specifies the test name

AcquireType - Specifies the acquire type

TRUE - Pop-ups are enabled

FALSE - Pop-ups are disabled



Tip: Check *Command parameters list* section for ParameterName and AcquireType parameters.

Outputs

Returns the value of Parameter for type GENERAL | ACQUIRE | ANALYZE | DUTID.

Command Parameters List

The section provides the parameters list for the SCPI commands.

Parameters	Description
InstrumentType	Specifies the instrument type. Valid values are: <ul style="list-style-type: none"> • AWG • AFG • Real Time Scope

Table continued...

Parameters	Description
Value	<p>Specifies the value parameters</p> <ul style="list-style-type: none"> For Instrument Type, valid values are <ul style="list-style-type: none"> Do not use MSO71254C (GPIB8::1::INSTR) For DUTID, valid value is: <ul style="list-style-type: none"> Comment
DeviceName	Specifies the device name. Valid value is Ethernet Tx
SuiteName	<p>Specifies the suite name.</p> <p>Valid values are:</p> <ul style="list-style-type: none"> 10GBASE-T 5GBASE-T 2.5GBASE-T
VersionName	Specifies the version name. Valid value is Spec 1.0
TestName	<p>Specifies the test measurement name.</p> <p>Valid values are:</p> <ul style="list-style-type: none"> Maximum Output Drop Power Spectrum Density Tone-1 Tone-2 Tone-3 Tone-4 Tone-5 Clock Frequency Jitter Master Jitter Slave Open Termination Short Termination Load Termination Return Loss

ParameterName and Value for General, Acquire and Analyze

Specifies the ParameterName and Value for General, Acquire and Analyze. The configuration parameters available are not same for measurements.

Table 16: ParameterName and Value for General

ParameterName	Value
Report Update Mode	<ul style="list-style-type: none"> • New • Append • Replace
Auto increment report name if duplicate	TRUE or FALSE
Include Pass/Fail Results Summary	TRUE or FALSE
Include Detailed Results	TRUE or FALSE
Include Plot Images	TRUE or FALSE
Include Setup Configuration	TRUE or FALSE
Include User Comments	TRUE or FALSE
Save As Type	<ul style="list-style-type: none"> • Web Archive (*.mht;*.mhtml) • PDF(*.pdf;)
View Report After Generating	TRUE or FALSE
Report Group Mode	<ul style="list-style-type: none"> • Test Name • Lane Name • Test Result • Equalization
Create report at the end	<ul style="list-style-type: none"> • Included • Excluded
DUTID Comment	User comment
Number of retries for instrument IO errors	0 to 5
Run Test More than Once	TRUE or FALSE
Number of Runs	1 to 200
On Failure Return	TRUE or FALSE
Number of Reruns On Failure	1 to 100
Time between retries (seconds)	5 to 60
Timer Warning Info Message Popup	<ul style="list-style-type: none"> • "TRUE" • "FALSE"
Timer Warning Info Message Popup Duration	0 to 20
Timer Error Message Popup	<ul style="list-style-type: none"> • "TRUE" • "FALSE"
Timer Error Message Popup Duration	0 to 20
On Failure Stop and Notify	TRUE or FALSE
Specification Details	<ul style="list-style-type: none"> • IEEE P802.3bz, Section 16; NBASE-T Spec Draft 2.3

Table continued...

ParameterName	Value
Probing Type	<ul style="list-style-type: none"> • SINGLE ENDED • Differential
Link Widths	<ul style="list-style-type: none"> • 1 Lane • 2 Lanes • 3 Lanes • 4 Lanes
Signal Validation	<ul style="list-style-type: none"> • Prompt me if Signal Validation Fails • Skip Test if Signal Validation Fails • Use signal as is - Don't Validate
Lane A:Lane A	<ul style="list-style-type: none"> • Included • Excluded
Lane B:Lane B	<ul style="list-style-type: none"> • Included • Excluded
Lane C:Lane C	<ul style="list-style-type: none"> • Included • Excluded
Lane D:Lane D	<ul style="list-style-type: none"> • Included • Excluded
Lane A Connected to:Lane A:Differential	<ul style="list-style-type: none"> • CH1 • CH2 • CH3 • CH4
Lane B Connected to:Lane B:Differential	
Lane C Connected to:Lane C:Differential	
Lane D Connected to:Lane D:Differential	
Lane A Connected to:Lane A+:Single Ended	
Lane A Connected to:Lane A-:Single Ended	
Lane A Connected to:Lane B+:Single Ended	
Lane A Connected to:Lane B-:Single Ended	

Table 17: ParameterName and Value for Acquire

Test Name	AcquireType	ParameterName	Value
Maximum Ouput Droop	Maximum Output Droop-Acquisition	Population	100 to 500 (units - clock cycles)
Power Spectrum Density	Power Spectrum Density-acquisition	AcquisitionAverage	2 to 256

Table continued...

Test Name	AcquireType	ParameterName	Value
Tone-1	Tone-1-Acquisition	AcquisitionAverage	2 to 100
		Execute with disturbing signal	<ul style="list-style-type: none"> "TRUE" "FALSE"
		Combiner Effect	0 to 10
		Compensation	1 to 30
Tone-2	Tone-2-Acquisition	AcquisitionAverage	2 to 100
		Execute with disturbing signal	<ul style="list-style-type: none"> "TRUE" "FALSE"
		Combiner Effect	0 to 10
		Compensation	1 to 30
Tone-3	Tone-3-Acquisition	AcquisitionAverage	2 to 100
		Execute with disturbing signal	<ul style="list-style-type: none"> "TRUE" "FALSE"
		Combiner Effect	0 to 10
		Compensation	1 to 30
Tone-4	Tone-4-Acquisition	AcquisitionAverage	2 to 100
		Execute with disturbing signal	<ul style="list-style-type: none"> "TRUE" "FALSE"
		Combiner Effect	0 to 10
		Compensation	1 to 30
Tone-5	Tone-5-Acquisition	AcquisitionAverage	2 to 100
		Execute with disturbing signal	<ul style="list-style-type: none"> "TRUE" "FALSE"
		Combiner Effect	0 to 10
		Compensation	1 to 30
Clock Frequency	Clock Frequency Acquisition	Population	10000 to 2000000 (clock cycles) for data rate - 10G 100 to 2000000 (clock cycles) for data rate -5G and 2.5G
Jitter Master	Jitter Master-Acquisition	AcquisitionDuration	0.1 ms to 10 ms
Jitter Slave	Jitter Slave -Acquisition	AcquisitionDuration	0.1 to 10
Open Termination	Open Termination- Acquisition	AcquisitionAverage	2 to 128
Short Termination	Short Termination-Acquisition	AcquisitionAverage	2 to 128
Load Termination	Load Termination-Acquisition	AcquisitionAverage	2 to 128

Table continued...

Test Name	AcquireType	ParameterName	Value
Return Loss	Return Loss-Acquisition	AcquisitionAverage	0 to 10 2 to 128

Table 18: ParameterName and Value for Analyze

Test Name	ParameterName	Value
Maximum Output Droop	RefLevel	<ul style="list-style-type: none"> Percentage Absolute
	MidLevel	If Ref Level is Percentage then 20 to 80 If Ref Level is Absolute then -10 mV to 10 mV
	Hysteresis	If Ref Level is Percentage then 2 to 20 If Ref Level is Absolute then 0 to 4
	StartTime	5 ns to 15 ns
	EndTime	<ul style="list-style-type: none"> For 10GBASE-T, 85 ns to 95 ns For 5GBASE-T, 160 ns to 180 ns For 2.5GBASE-T, 320 ns to 340 ns
Power Spectrum Density	StartFrequency	1 MHz to 1500 MHz
	StopFrequency	1600 MHz to 4000 MHz
	ResolutionBandwidth	1 MHz to 5 MHz
	PowerLevelStartFrequency	1 MHz to 1500 MHz
	PoerLevelStopFrequency	1600 MHz to 4000 MHz
	Smoothing Average	1 to 100
Tone-1	StartFrequency	1 kHz to 30000 kHz
	StopFrequency	350000 kHz to 800000 kHz
	ResolutionBandwidth	20 kHz to 500 kHz
	Apply Filter	<ul style="list-style-type: none"> True False
Tone-2	StartFrequency	1 kHz to 30000 kHz
	StopFrequency	350000 kHz to 800000 kHz
	ResolutionBandwidth	20 kHz to 500 kHz
	Apply Filter	<ul style="list-style-type: none"> True False

Table continued...

Test Name	ParameterName	Value
Tone-3	StartFrequency	1 kHz to 30000 kHz
	StopFrequency	350000 kHz to 800000 kHz
	ResolutionBandwidth	20 kHz to 500 kHz
	Apply Filter	<ul style="list-style-type: none"> • True • False
Tone-4	StartFrequency	1 kHz to 30000 kHz
	StopFrequency	350000 kHz to 800000 kHz
	ResolutionBandwidth	20 kHz to 500 kHz
	Apply Filter	<ul style="list-style-type: none"> • True • False
Tone-5	StartFrequency	1 kHz to 30000 kHz
	StopFrequency	350000 kHz to 800000 kHz
	ResolutionBandwidth	20 kHz to 500 kHz
	Apply Filter	<ul style="list-style-type: none"> • True • False
Clock Frequency	RefLevel	<ul style="list-style-type: none"> • Percentage • Absolute
	MidLevel	If Ref Level is Percentage then 20 to 80 If Ref Level is Absolute then -10 mV to 10 mV
	Hysteresis	If Ref Level is Percentage then 2 to 20 If Ref Level is Absolute then 0 mV to 4 mV
Jitter Master	RefLevel	<ul style="list-style-type: none"> • Percentage • Absolute
	MidLevel	If Ref Level is Percentage then 20 to 80 If Ref Level is Absolute then -10 mV to 10 mV
	Hysteresis	If Ref Level is Percentage then 2 to 20 If Ref Level is Absolute then 0 mV to 4 mV
Table continued...		

Test Name	ParameterName	Value
Jitter Slave	RefLevel	<ul style="list-style-type: none"> Percentage Absolute
	MidLevel	If Ref Level is Percentage then 20 to 80 If Ref Level is Absolute then -10 mV to 10 mV
	Hysteresis	If Ref Level is Percentage then 2 to 20 If Ref Level is Absolute then 0 mV to 4 mV
Open Termination	SmoothingAverage	1 to 10
Short Termination	SmoothingAverage	1 to 10
Load Termination	SmoothingAverage	1 to 10
Return Loss	SmoothingAverage	1 to 10

Examples

This section provides the examples for the SCPI commands.

Example	Description
TEKEXP:*IDN?\n	It returns the active TekExpress application name running on the scope.
TEKEXP:*OPC?\n	It returns the last command execution status, if status is executed it returns "1" else "0".
TEKEXP:ACQUIRE_MODE PRE-RECORDED\n	It sets the acquire mode as pre-recorded.
TEKEXP:ACQUIRE_MODE?\n	It returns LIVE when acquire mode is set to live or it returns pre-recorded when acquire mode is set to pre-recorded.
TEKEXP:EXPORT REPORT\n	It returns the report file in bytes. This can be written into another file for further analysis.
TEKEXP:INFO? REPORT\n	It returns "100,"ReportFileName.mht", when 100 is the file size in bytes for the filename ReportFileName.
TEKEXP:INFO? WFM\n	It returns "100,"WfmFileName1.wfm";"200, "WfmFileName2.wfm"" when 100 is the filesize in bytes for the filename WfmFileName1.wfm and 200 is the file size in bytes for the filename WfmFileName2.wfm.
TEKEXP:INSTRUMENT "Real Time Scope",DPO73304SX (GPIB8::1::INSTR)\n	It sets the instrument value as DPO73304SX(GPIB8::1::INSTR) for the selected instrument type Real Time Scope.
TEKEXP:INSTRUMENT? "Real Time Scope"\n	It returns "DPO73304SX (GPIB8::1::INSTR)", when DPO73304SX (GPIB8::1::INSTR) is the selected instrument for the instrument type Real Time Scope.
TEKEXP:LASTERROR?\n	It returns ERROR: INSTRUMENT_NOT_FOUND, when no instrument is found.
TEKEXP:LIST? DEVICE\n	It returns "USB4" when TX-Device, RXDevice are the available device.
TEKEXP:LIST? INSTRUMENT, "Real Time Scope"\n	It returns "DPO73304SX (GPIB8::1::INSTR), DPO73304DX (TCPIP::134.64.248.91::INSTR)" when DPO73304SX (GPIB8::1::INSTR), DPO73304DX (TCPIP::134.64.248.91::INSTR) are the list of available instruments.
TEKEXP:MODE COMPLIANCE\n	It sets the execution mode as compliance.

Table continued...

Example	Description
TEKEXP:MODE?\n	It returns COMPLIANCE when the execution mode is compliance or It returns USER-DEFINED when the execution mode is user defined.
TEKEXP:POPUP "OK"\n	It sets OK as the response to active popup in the application.
TEKEXP:POPUP?\n	It returns "OK", when OK is the active popup information shown in the application.
TEKEXP:REPORT GENERATE\n	It generates report for the current session.
TEKEXP:REPORT? "Scope Model"\n	Returns "DPO73304SX" when DPO73304SX is the scope model.
TEKEXP:REPORT? "DUT ID"\n	It returns "DUT001" when DNI_DUT001 is the DUT ID.
TEKEXP:RESULT? "Period using SCOPE (Acquire-Analyze Combined)"\n	It returns Pass when the test result is Pass.
TEKEXP:RESULT? "Period using SCOPE (Acquire-Analyze Combined)", "Margin", 1\n	It returns "L:-50.000ps H:2000.000ps" when L:-50.000ps H:2000.000ps is the value.
TEKEXP:SELECT DEVICE, TX_Device, TRUE\n	It selects TX_Device
TEKEXP:SELECT? DEVICE\n	It returns USB4
TEKEXP:SETUP DEFAULT\n	It restores the application to default setup.
TEKEXP:STATE STOP\n	It stops the test execution.
TEKEXP:STATE?\n	It returns as READY when the application is ready to run next measurement.
TEKEXP:STATE? SETUP\n	It returns as NOT_SAVED when the current setup is not saved else it returns SAVED.
TEKEXP:VALUE GENERAL, "Signal Type", "N1N0"\n	It sets the signal type parameter value to N1N0.
TEKEXP:VALUE? GENERAL, "Signal Type"\n	It returns "N1N0" when N1N0 is the Signal Type value.

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